Digital-to-Analog and Analog-to-Digital Converters

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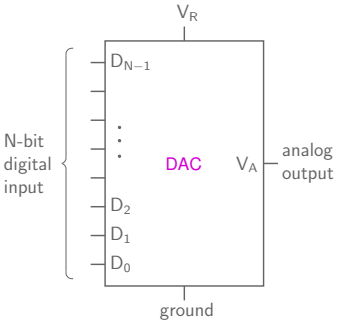
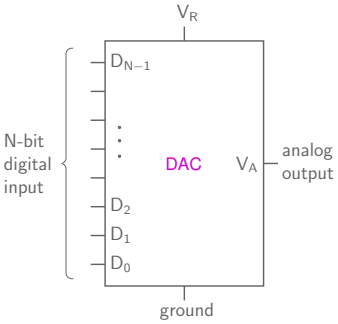
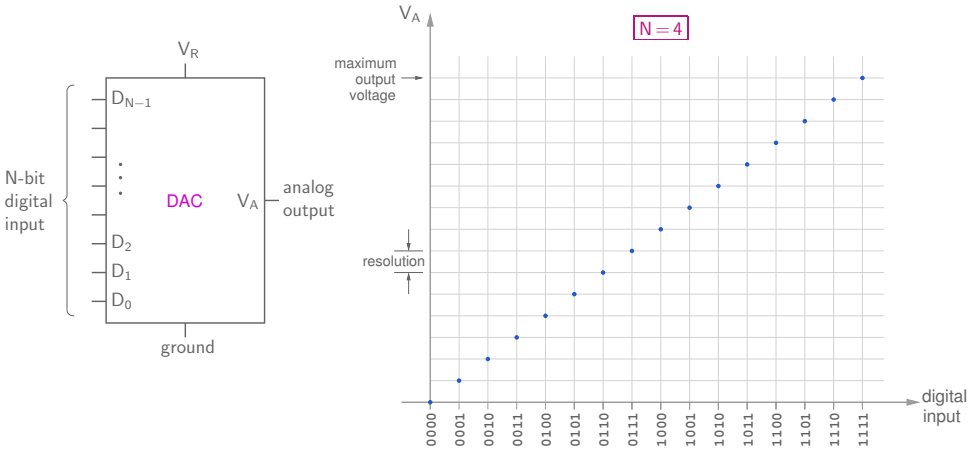
DAC


V_R
D_{N-1}
N-bit
digital
input
DAC
V_A
analog
output
D_2
D_1
D_0
ground



* For a 4-bit DAC, with input $S_3S_2S_1S_0$, the output voltage is $V_A = K\left[(S_3 \times 2^3) + (S_2 \times 2^2) + (S_1 \times 2^1) + (S_0 \times 2^0)\right]$.
  In general, $V_A = K \sum_0^{N-1} S_k 2^k$.



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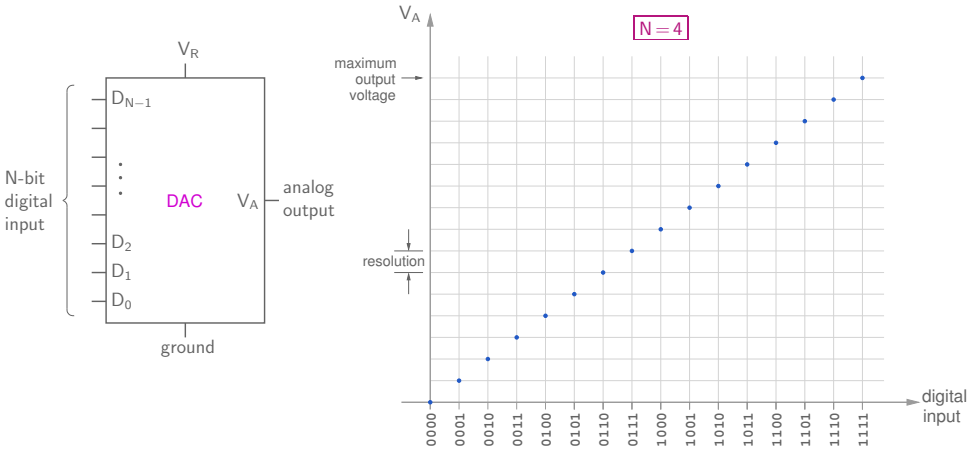

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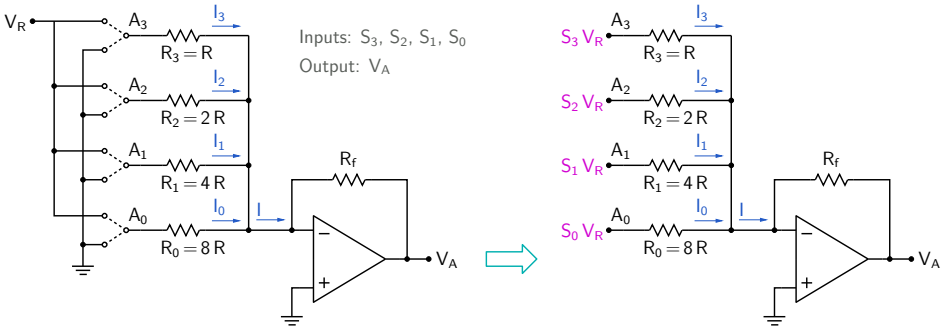
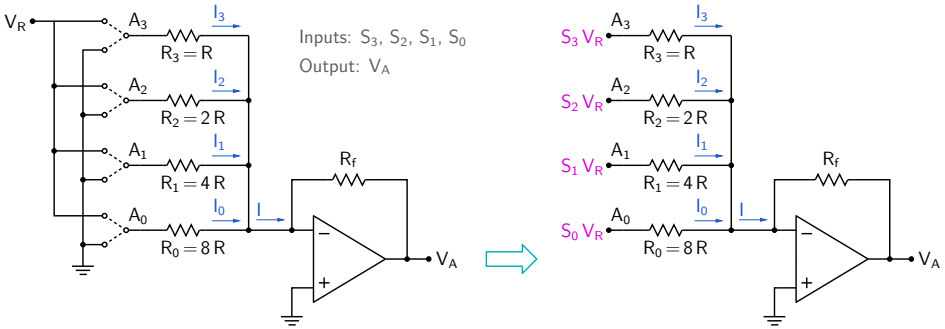
* K is proportional to the reference voltage V_R. Its value depends on how the DAC is implemented.


V_R
A_3
I_3
$R_3 = R$
A_2
I_2
$R_2 = 2R$
A_1
I_1
$R_1 = 4R$
A_0
I_0
$R_0 = 8R$
I
R_f
V_A
Inputs: S_3, S_2, S_1, S_0
Output: V_A
$S_3 V_R$
$S_2 V_R$
$S_1 V_R$
$S_0 V_R$



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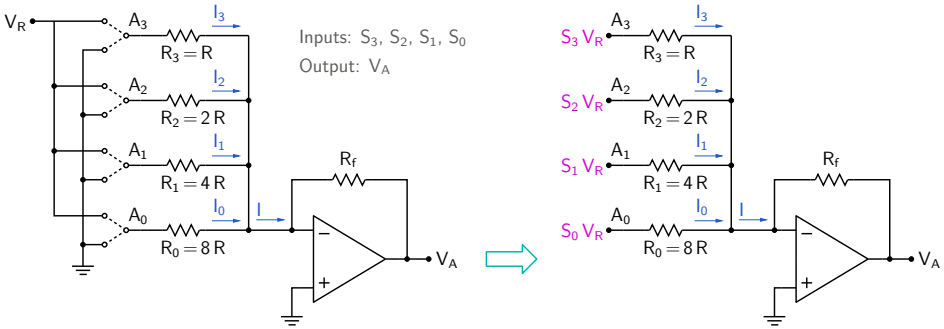
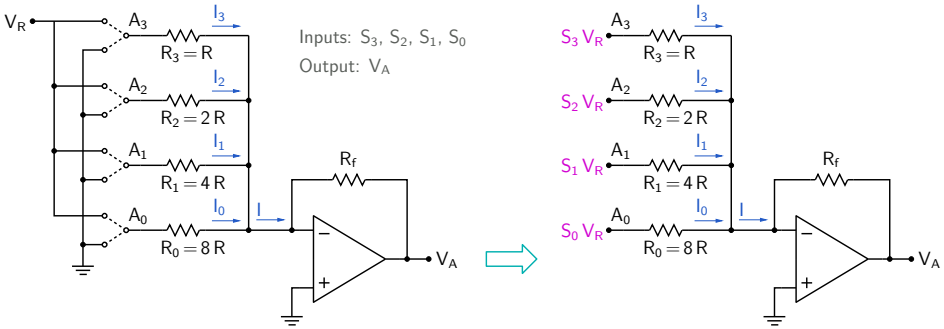


* If the input bit S_k is 1, A_k gets connected to V_R; else, it gets connected to ground. $\rightarrow V(A_k) = S_k \times V_R$.



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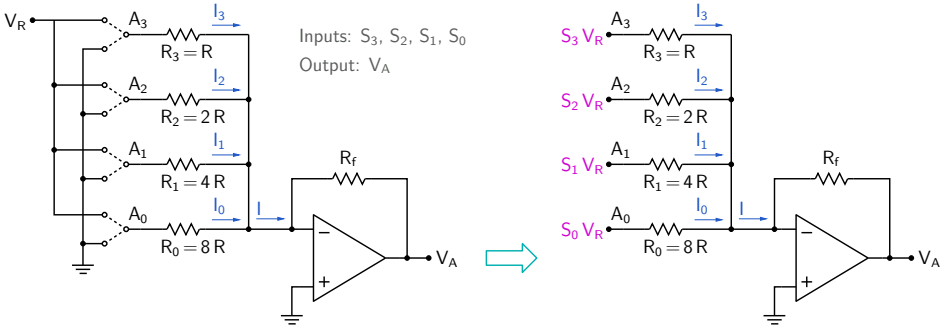

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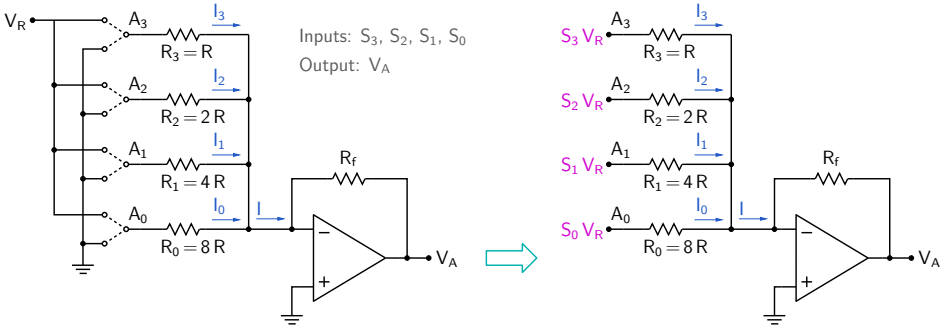
* $I = \dfrac{S_0 V_R}{8R} + \dfrac{S_1 V_R}{4R} + \dfrac{S_2 V_R}{2R} + \dfrac{S_3 V_R}{R} = \dfrac{V_R}{2^{N-1}R} \sum_{0}^{N-1} S_k \times 2^k \ (N = 4)$.

DAC using binary-weighted resistors



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* The output voltage is $V_o = -R_f\, I = -V_R \dfrac{R_f}{2^{N-1}R} \sum_0^{N-1} S_k \times 2^k$.

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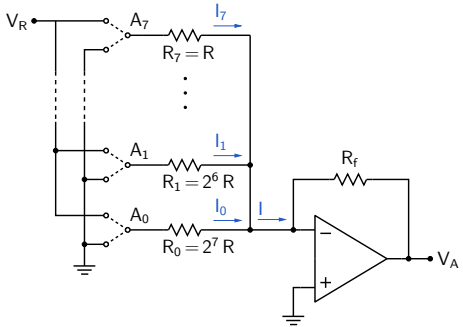

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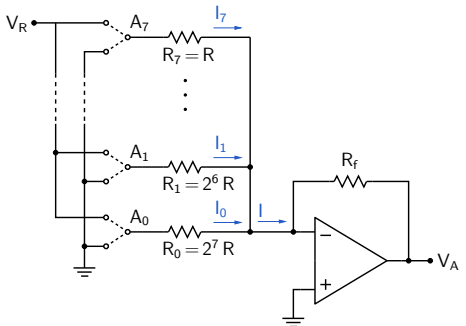

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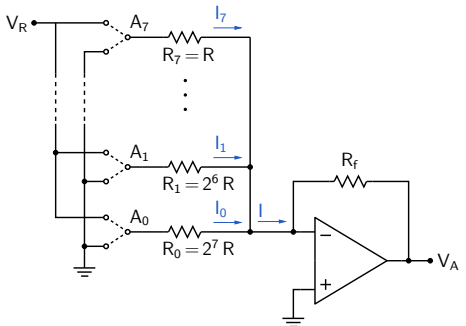

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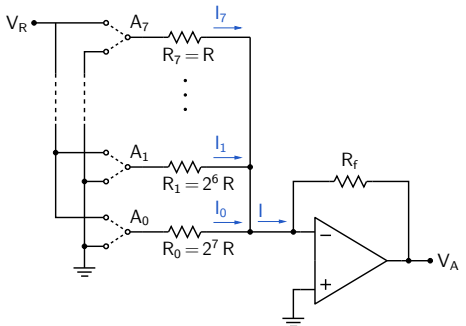

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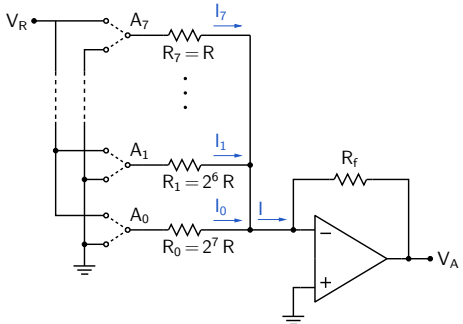

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  $$\rightarrow 10\,\text{mA} = \frac{V_R}{R} + \frac{V_R}{2R} + \cdots + \frac{V_R}{2^7 R} = \frac{1}{2^7}\,\frac{V_R}{R}\left(2^0 + 2^1 + \cdots + 2^7\right)$$

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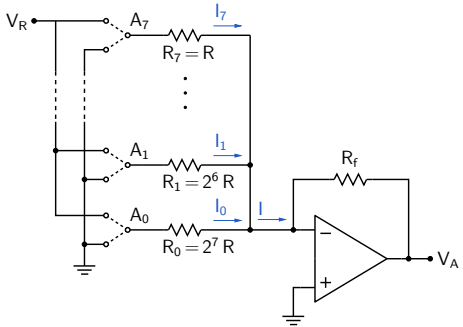

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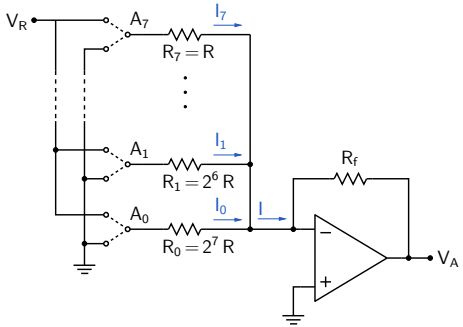
(Ref.: K. Gopalan, *Introduction to Digital Microelectronic Circuits*, Tata McGraw-Hill, New Delhi, 1998)

DAC using binary-weighted resistors: Example (from Gopalan)



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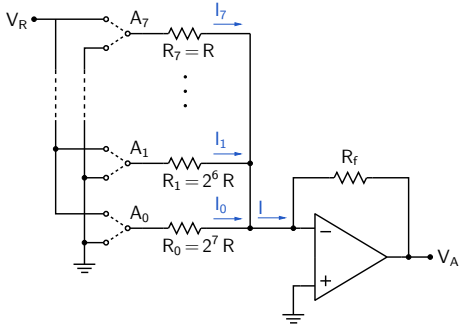

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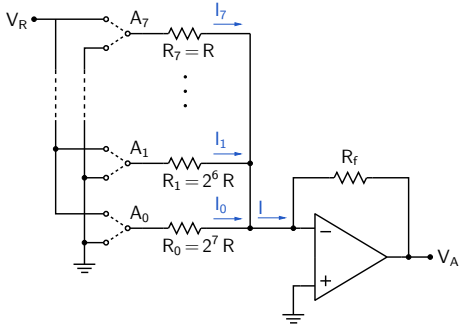

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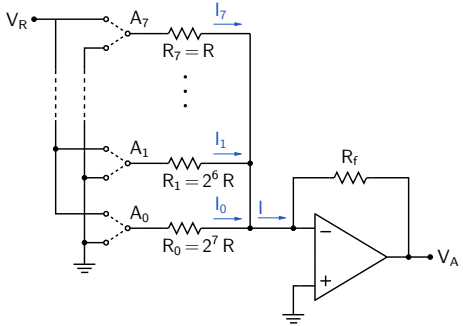

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$$\rightarrow \Delta V_A = \frac{V_R}{2^{N-1}}\frac{R_f}{R} = \frac{5\,\text{V}}{2^{8-1}} \times 1 = \frac{5}{128} = 0.0391\,\text{V}.$$

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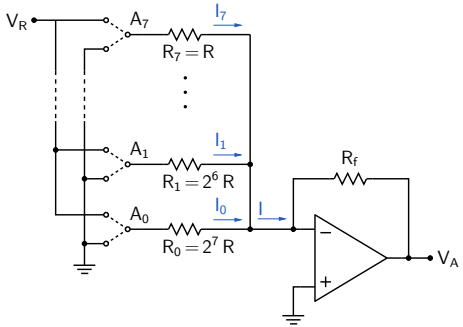

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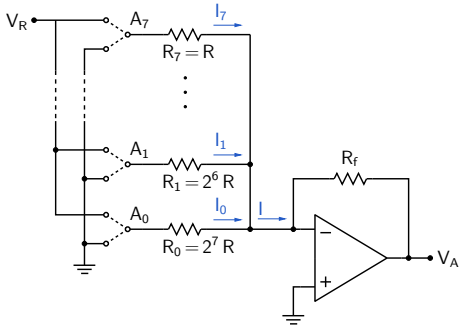

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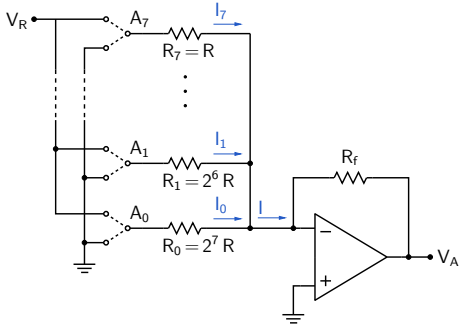

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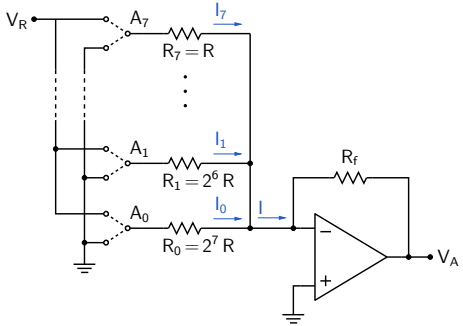

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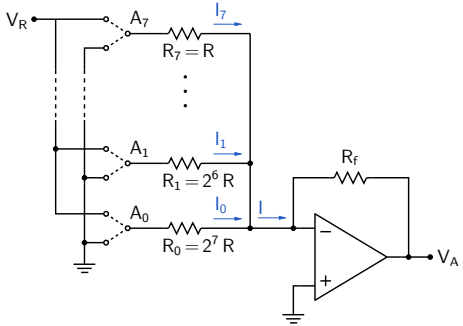

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$$|V_A|^{\max} = \frac{5}{128} \times 1 \times \left[2^0 + 2^1 + \cdots + 2^7\right] = \frac{5}{128} \times \left(2^8 - 1\right) = 5 \times \frac{255}{128} = 9.961\,\text{V}.$$

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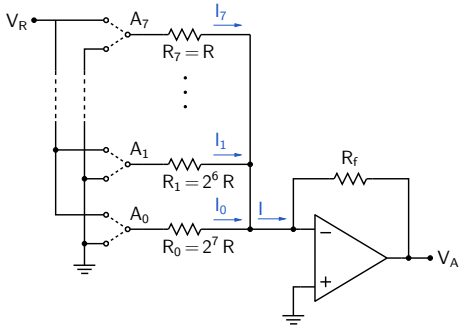

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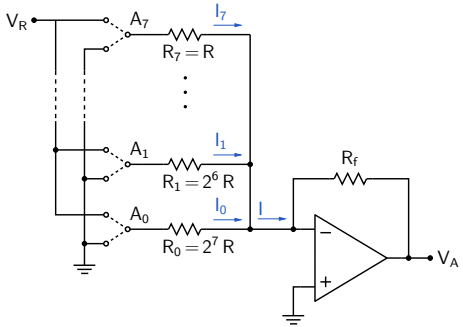

* Find the output voltage corresponding to the input 1010 1101.

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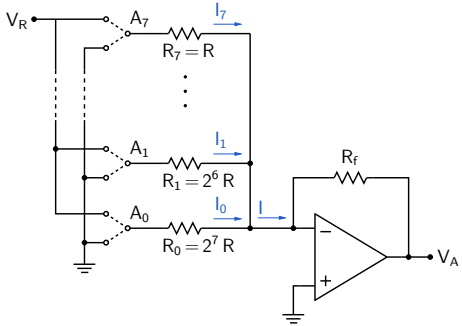

* Find the output voltage corresponding to the input 1010 1101.

$$V_A = -\frac{V_R}{2^{N-1}}\,\frac{R_f}{R}\left[S_7 2^7 + \cdots + S_1 2^1 + S_0 2^0\right].$$

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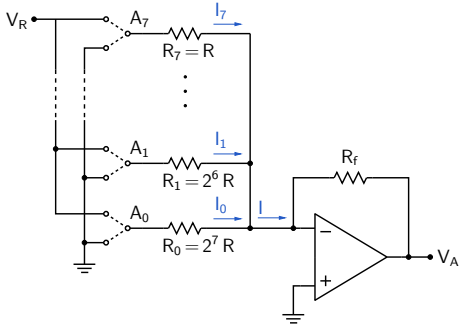

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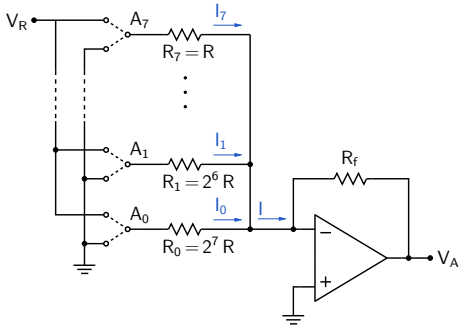
$$V_A = -\frac{V_R}{2^{N-1}}\,\frac{R_f}{R}\left[S_7 2^7 + \cdots + S_1 2^1 + S_0 2^0\right].$$

$$= -\frac{5}{128} \times 1 \times \left[2^7 + 2^5 + 2^3 + 2^2 + 2^0\right] = -5 \times \frac{173}{128} = -6.758\,\text{V}.$$

DAC using binary-weighted resistors: Example (from Gopalan)



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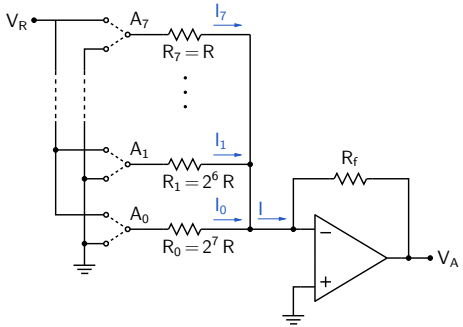

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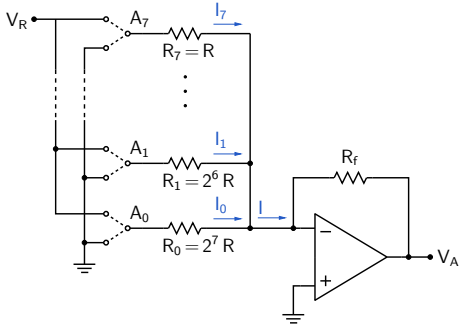

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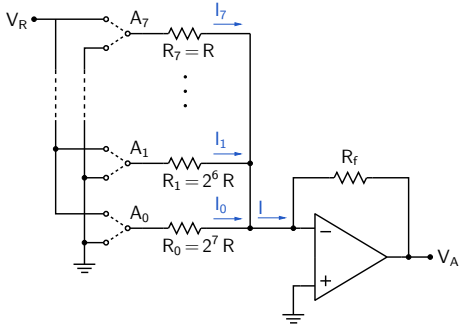

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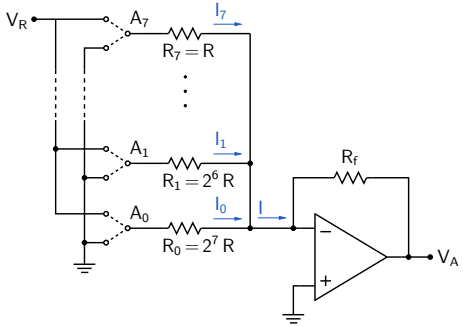

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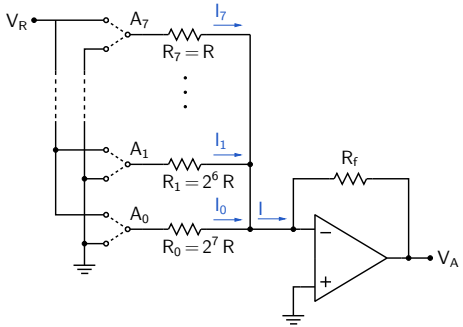
  Similarly, $|V_A|^{\text{min}}_{11111111} = 5 \times \frac{255}{128} \times \frac{0.99}{1.01} = 9.764\,\text{V}.$

DAC using binary-weighted resistors: Example (from Gopalan)



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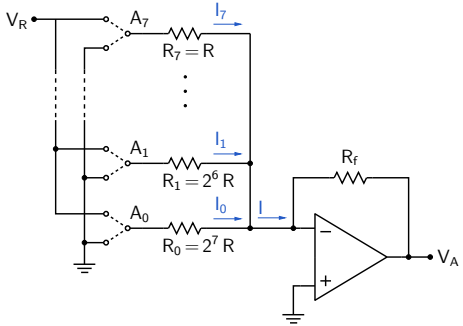

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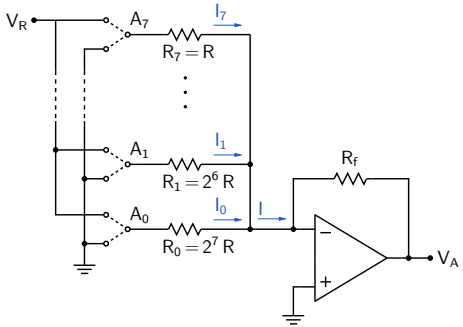

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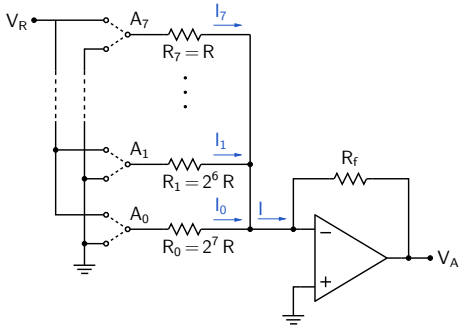

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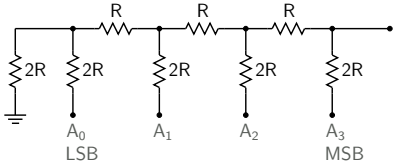
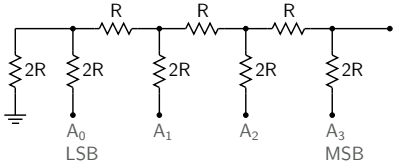
* The output voltage variation can be reduced by using resistors with a smaller tolerance. However, it is difficult to fabricate an IC with widely varying resistance values (from R to $2^{N-1}R$) and each with a small enough tolerance.
  $\rightarrow$ use $R - 2R$ ladder network instead.

R-2R ladder network



Node A_k is connected to V_R if input bit S_k is 1; else, it is connected to ground.



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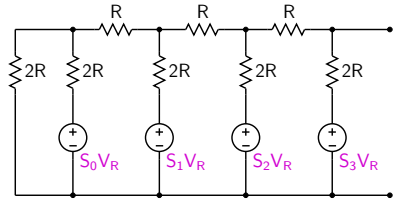
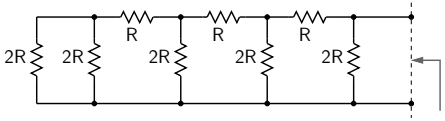
The original network is equivalent to



R-2R ladder network: Thevenin resistance



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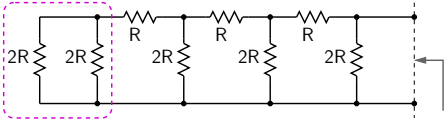

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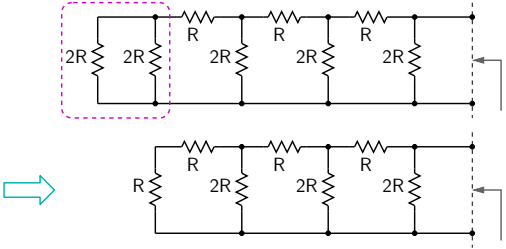

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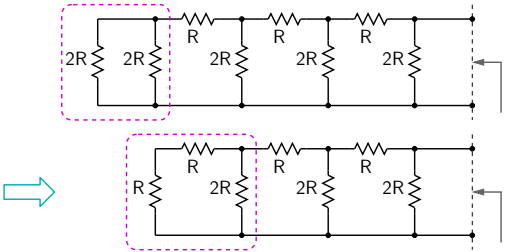

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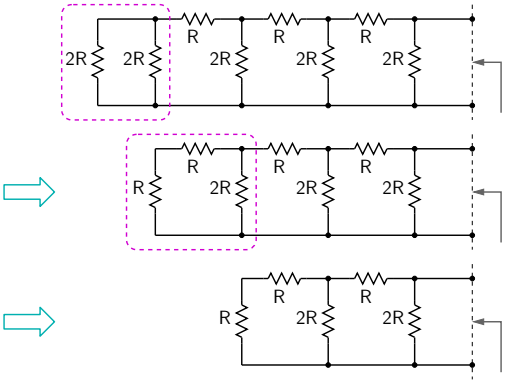

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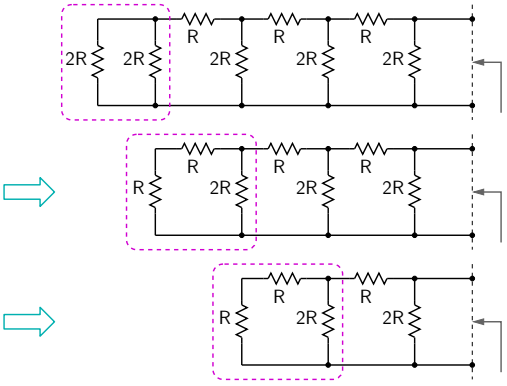

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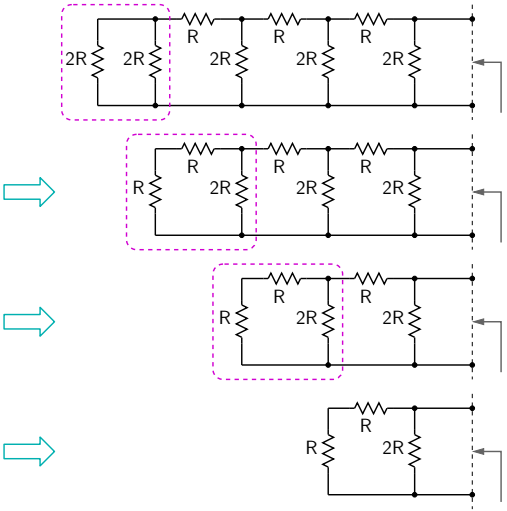

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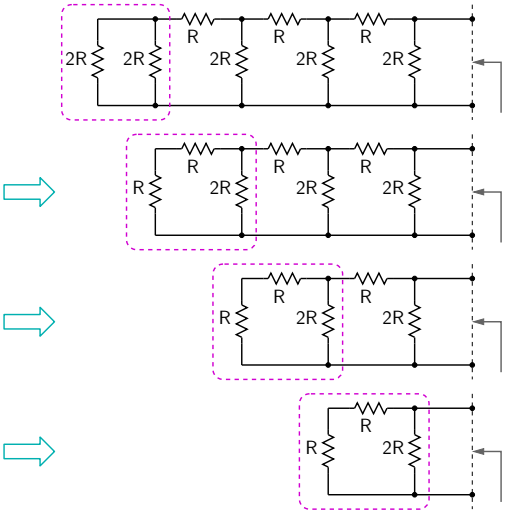

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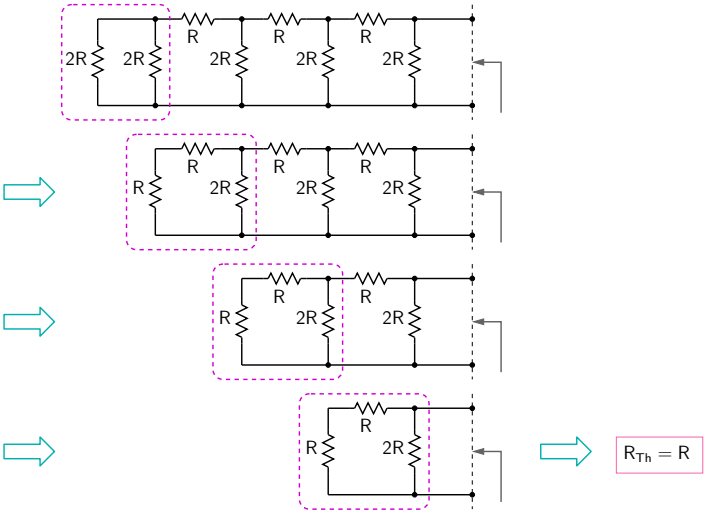
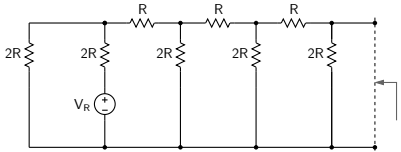


R-2R ladder network:
V_{Th} for $S_0 = 1$



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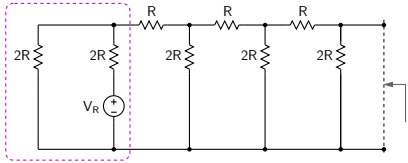

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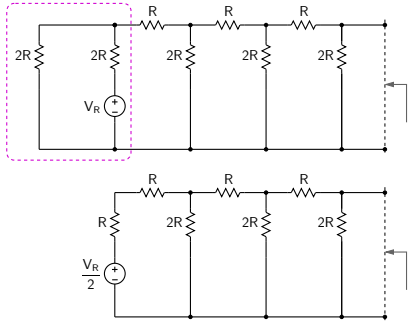

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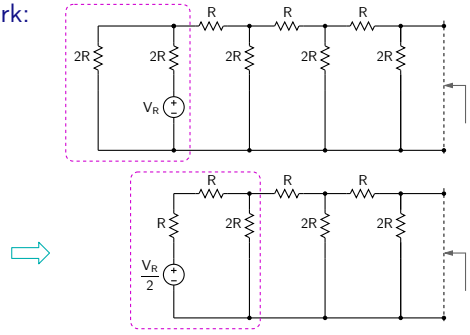

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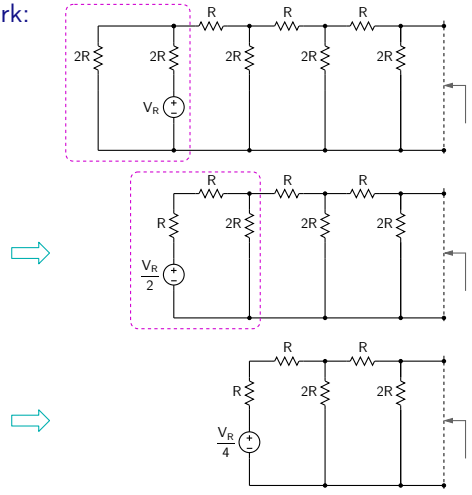

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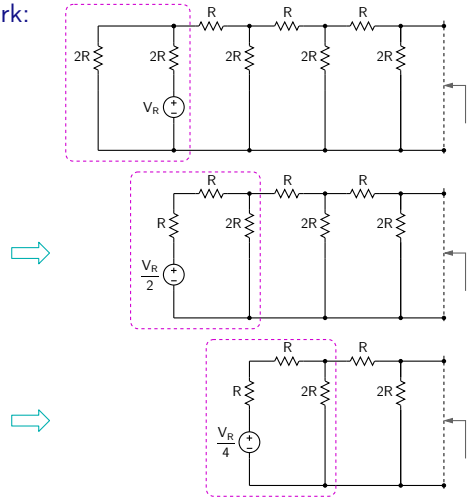

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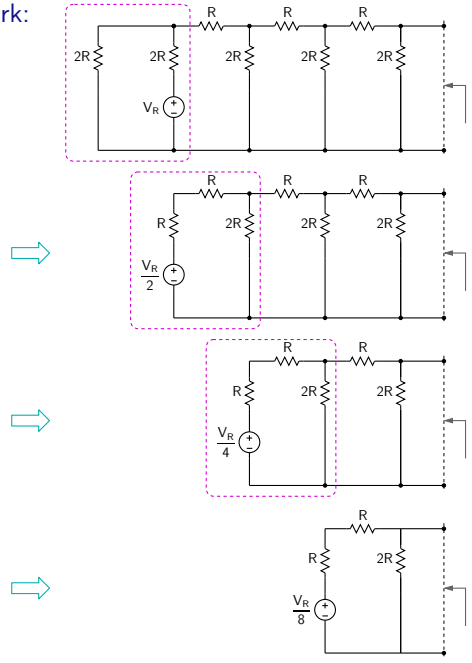

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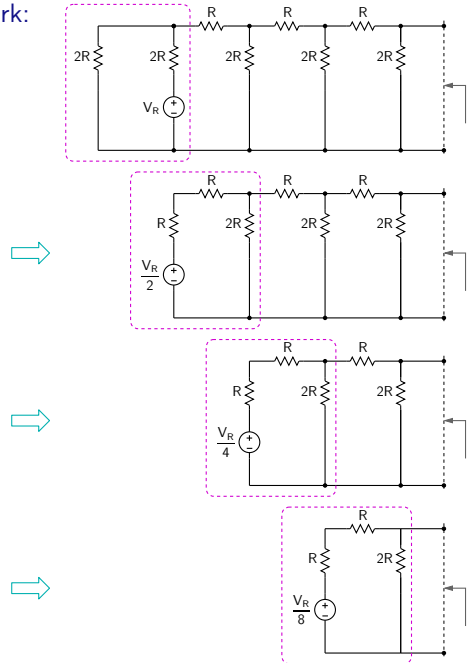

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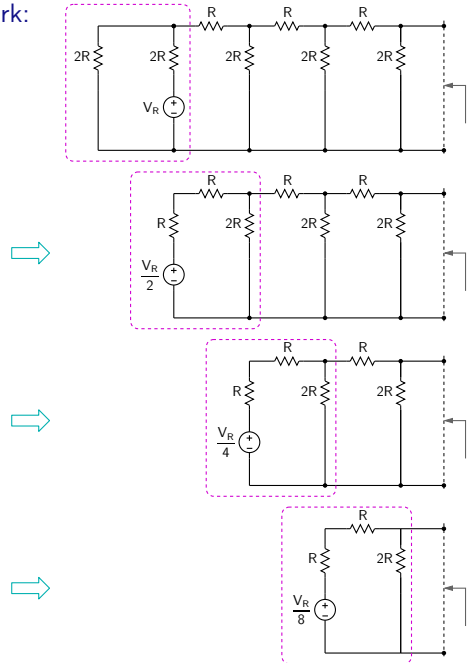

R-2R ladder network:
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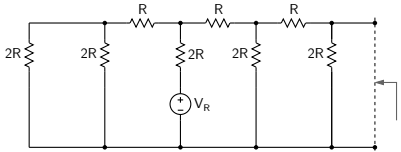

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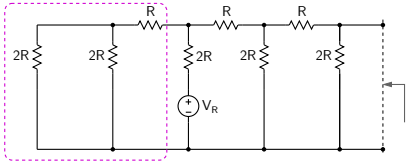

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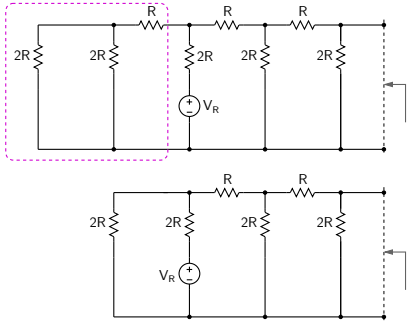

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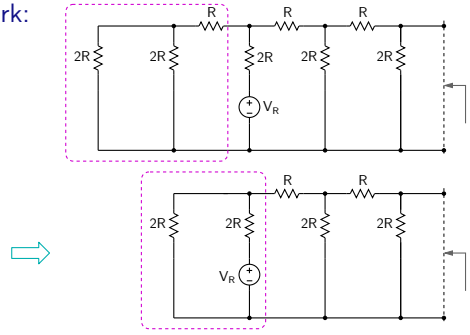

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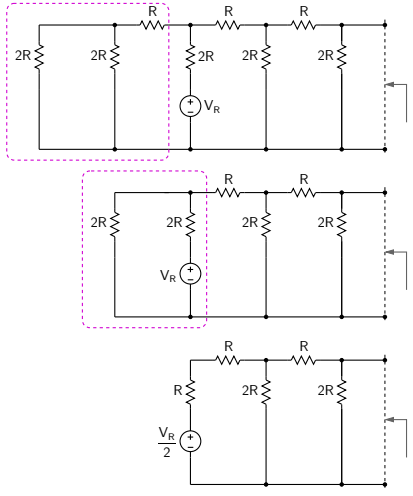

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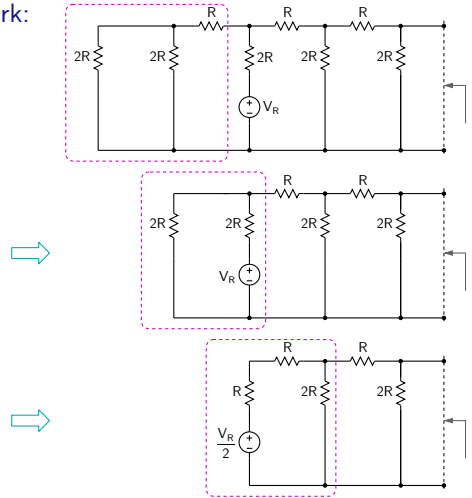

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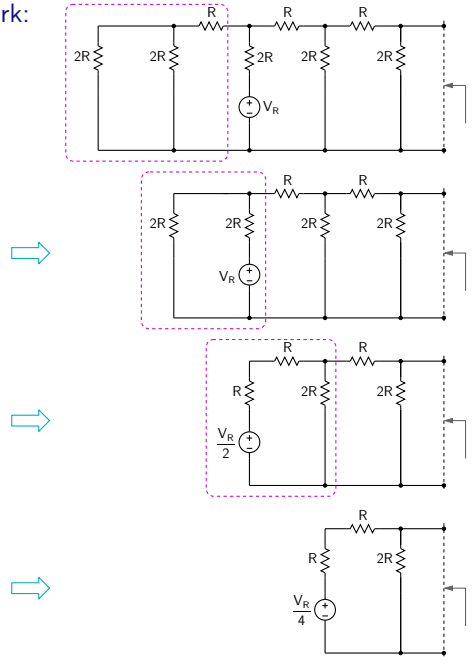

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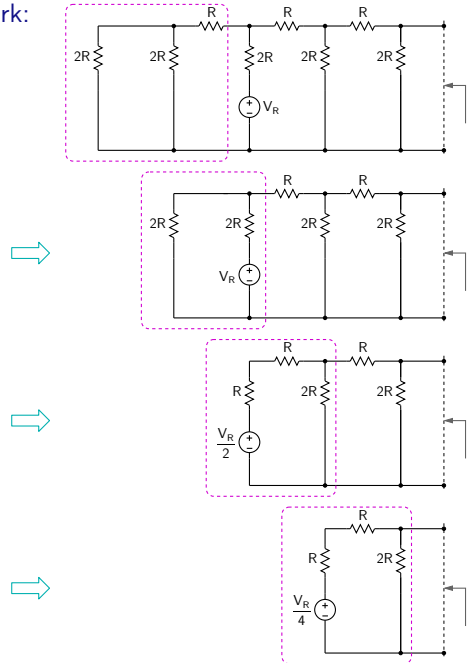

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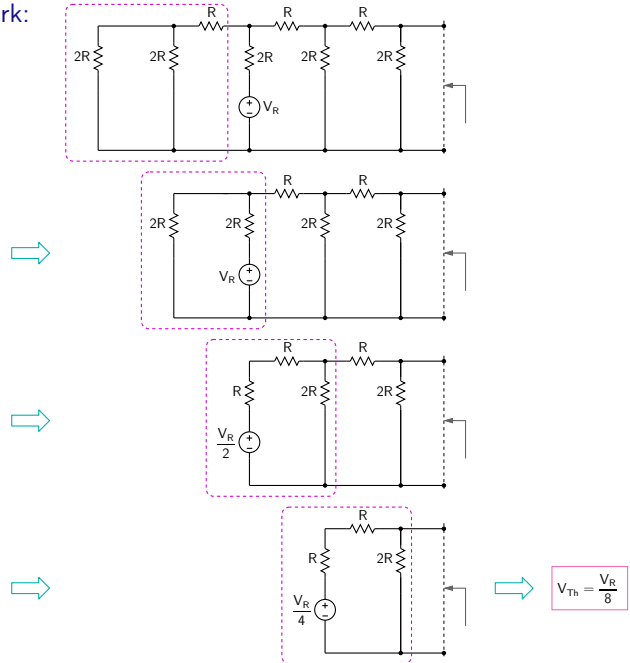
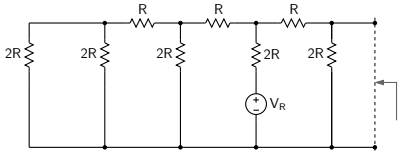


R-2R ladder network:
V_{Th} for $S_2 = 1$



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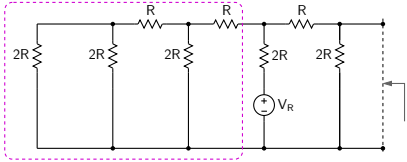

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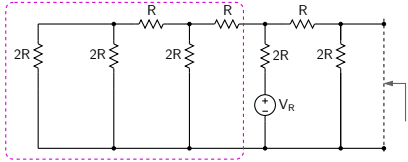
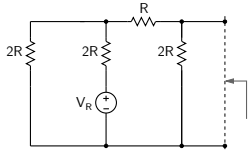
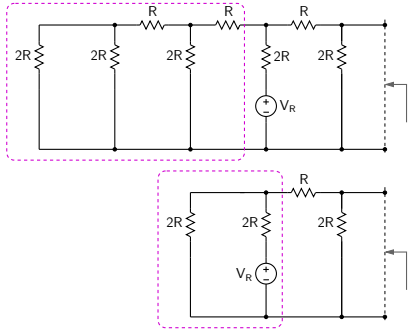
V_{Th} for $S_2 = 1$

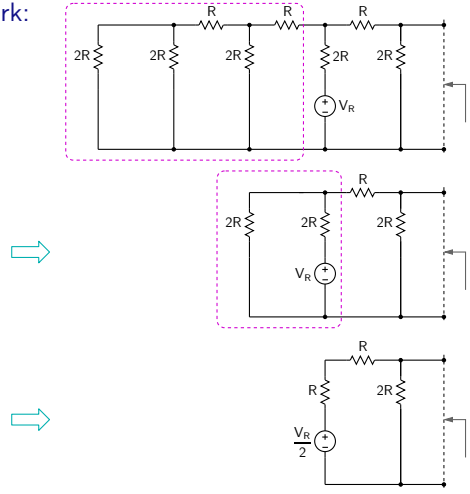




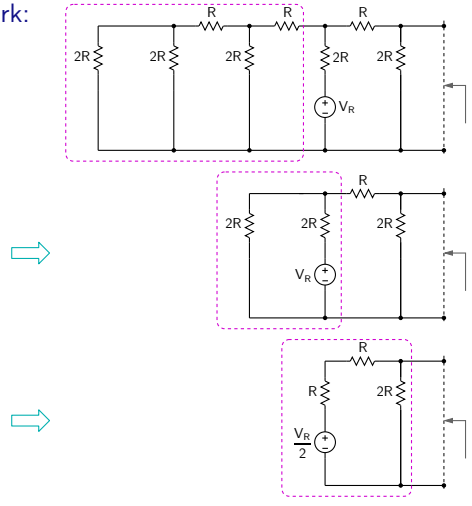
R-2R ladder network:
V_{Th} for $S_2 = 1$



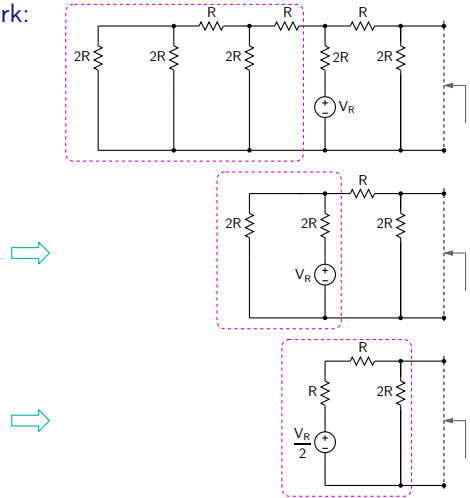
R-2R ladder network:
V_{Th} for $S_2 = 1$



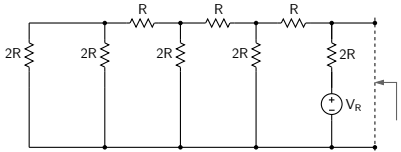
R-2R ladder network:
V_{Th} for $S_2 = 1$



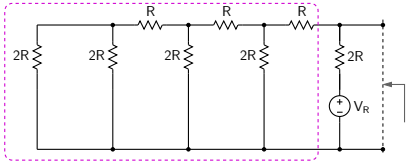
R-2R ladder network:
V_{Th} for $S_2 = 1$



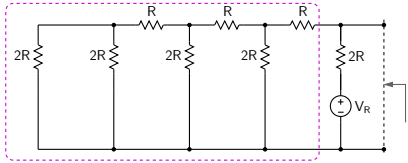
R-2R ladder network:
V_{Th} for $S_3 = 1$

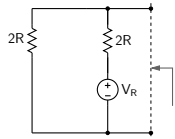


R-2R ladder network:
V_{Th} for $S_3 = 1$

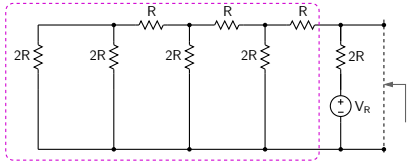


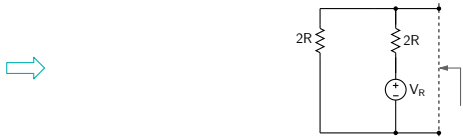
R-2R ladder network:
V_{Th} for $S_3 = 1$





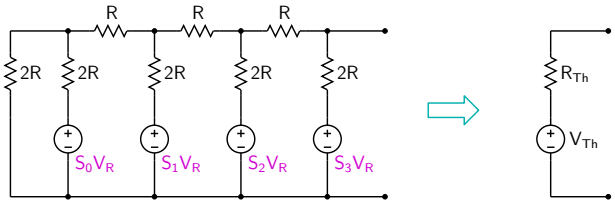
R-2R ladder network:
V_{Th} for $S_3 = 1$

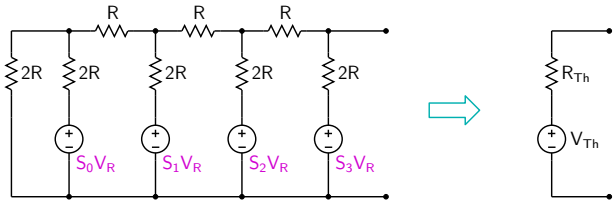




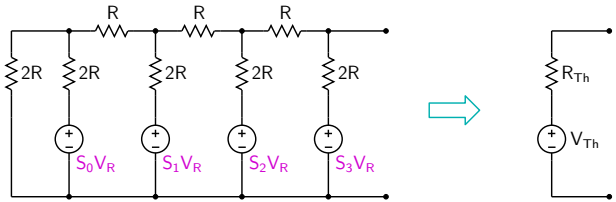
$$V_{Th} = \frac{V_R}{2}$$

R-2R ladder network: R_{Th} and V_{Th}



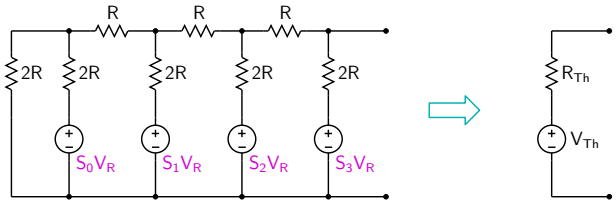


* $R_{Th} = R$.



* $R_{Th} = R$.
* $V_{Th} = V_{Th}^{(S0)} + V_{Th}^{(S1)} + V_{Th}^{(S2)} + V_{Th}^{(S3)}$

$$= \frac{V_R}{16}\left[S_0\,2^0 + S_1\,2^1 + S_2\,2^2 + S_3\,2^3\right] .$$



* $R_{Th} = R$.
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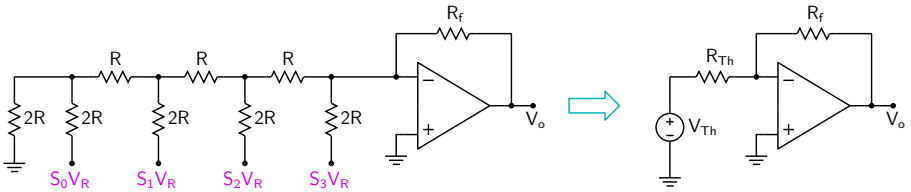
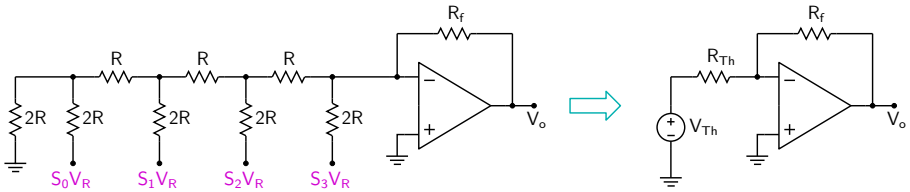
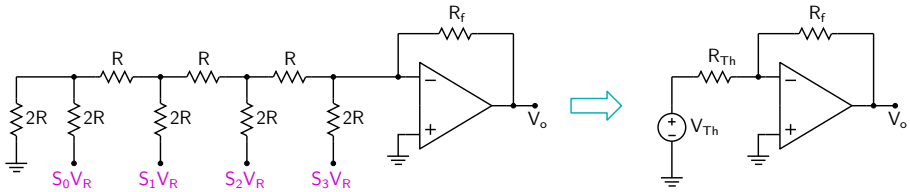
  $= \frac{V_R}{16}\left[S_0\,2^0 + S_1\,2^1 + S_2\,2^2 + S_3\,2^3\right]$.
* We can use the R-$2R$ ladder network and an op-amp to make up a DAC $\rightarrow$ next slide.


R
R
R
2R
2R
2R
2R
2R
R_f
V_o
S_0V_R
S_1V_R
S_2V_R
S_3V_R
R_{Th}
V_{Th}



* $V_o = -\dfrac{R_f}{R_{Th}}\, V_{Th} = -\dfrac{R_f}{R_{Th}}\, \dfrac{V_R}{16}\, \left[S_0\, 2^0 + S_1\, 2^1 + S_2\, 2^2 + S_3\, 2^3\right]$.



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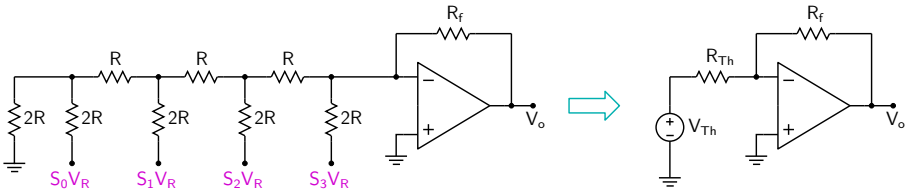
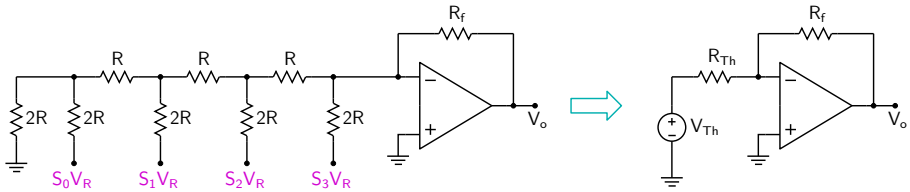
* For an N-bit DAC, $V_o = -\dfrac{R_f}{R_{Th}}\, V_{Th} = -\dfrac{R_f}{R_{Th}}\, \dfrac{V_R}{2^N}\, \sum_{0}^{N-1} S_k 2^k$.



* $V_o = -\dfrac{R_f}{R_{Th}}\, V_{Th} = -\dfrac{R_f}{R_{Th}}\, \dfrac{V_R}{16}\, \left[S_0\, 2^0 + S_1\, 2^1 + S_2\, 2^2 + S_3\, 2^3\right]$.
* For an N-bit DAC, $V_o = -\dfrac{R_f}{R_{Th}}\, V_{Th} = -\dfrac{R_f}{R_{Th}}\, \dfrac{V_R}{2^N}\, \sum_{0}^{N-1} S_k 2^k$.
* 6- to 20-bit DACs based on the R-2R ladder network are commercially available in monolithic form (single chip).



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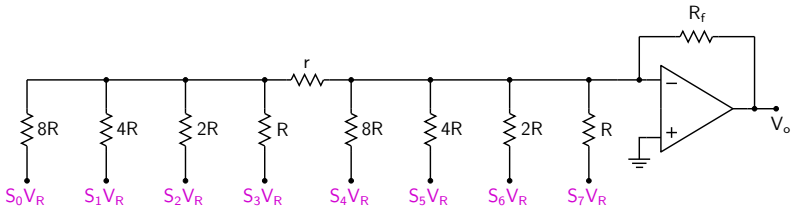
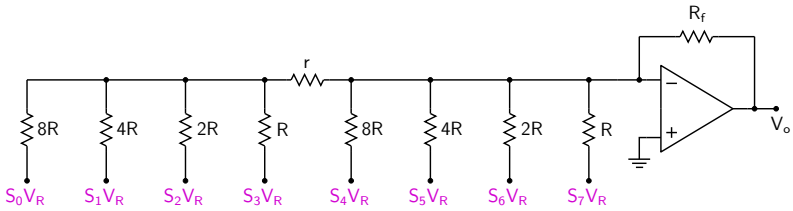
* 6- to 20-bit DACs based on the R-2R ladder network are commercially available in monolithic form (single chip).
* Bipolar, CMOS, or BiCMOS technology is used for these DACs.

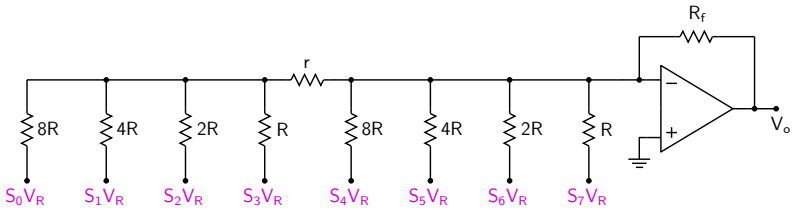


Combination of weighted–resistor and R–2R ladder networks



Combination of weighted–resistor and R–2R ladder networks

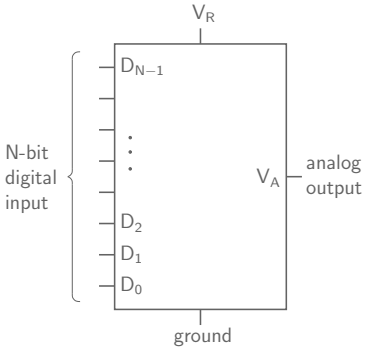
* Find the value of r for the circuit to work as a regular (i.e., binary to analog) DAC.

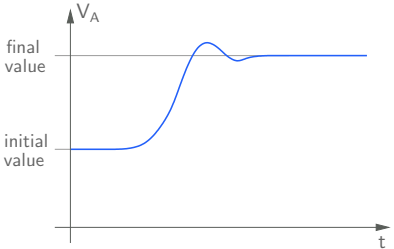


Combination of weighted–resistor and R–2R ladder networks

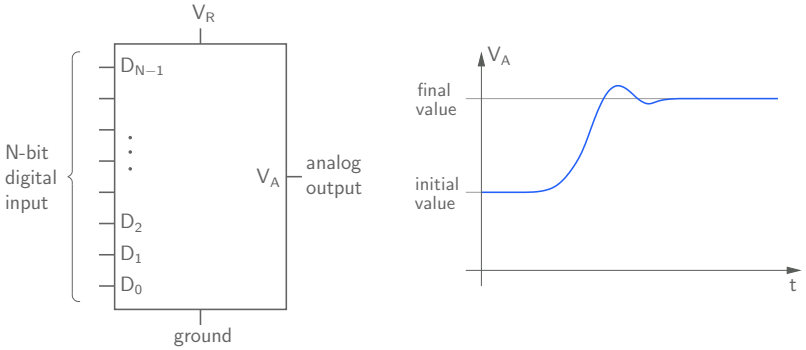
- Find the value of r for the circuit to work as a regular (i.e., binary to analog) DAC.
- Find the value of r for the circuit to work as a BCD to analog DAC.

DAC: settling time



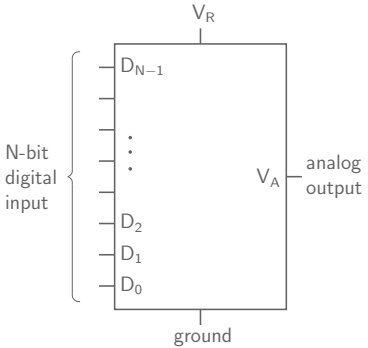


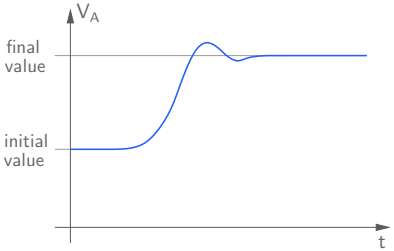
DAC: settling time



* When there is a change in the input binary number, the output V_A takes a finite time to settle to the new value.

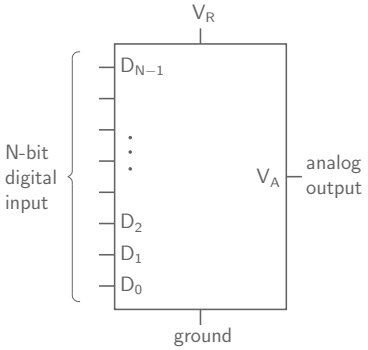
DAC: settling time

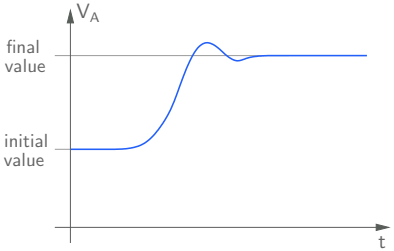




* When there is a change in the input binary number, the output V_A takes a finite time to settle to the new value.
* The finite settling time arises because of stray capacitances and switching delays of the semiconductor devices used within the DAC chip.

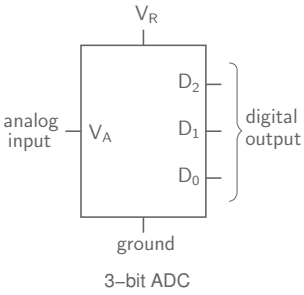
DAC: settling time

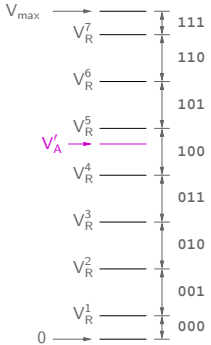


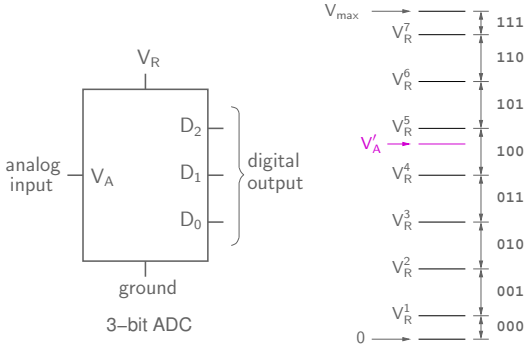


* When there is a change in the input binary number, the output V_A takes a finite time to settle to the new value.
* The finite settling time arises because of stray capacitances and switching delays of the semiconductor devices used within the DAC chip.
* Example: 500 ns to 0.2 % of full scale.

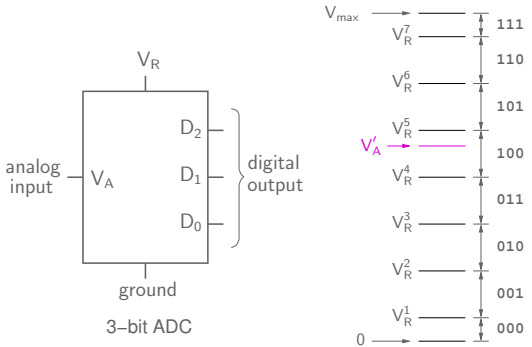
ADC: introduction







* If the input V_A is in the range $V_R^k < V_A < V_R^{k+1}$, the output is the binary number corresponding to the integer k. For example, for $V_A = V'_A$, the output is 100.



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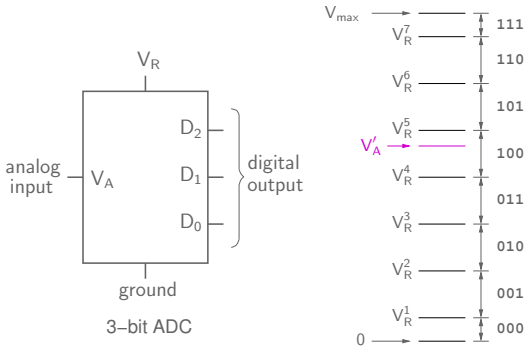
* We may think of each voltage interval (corresponding to 000, 001, etc.) as a "bin." In the above example, the input voltage V'_A falls in the 100 bin; therefore, the output of the ADC would be 100.



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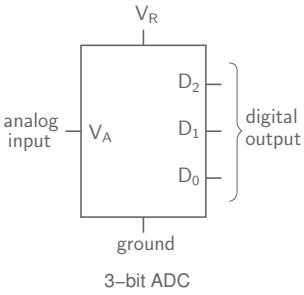
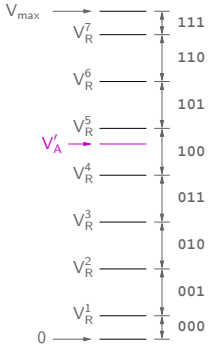
* We may think of each voltage interval (corresponding to 000, 001, etc.) as a "bin." In the above example, the input voltage V'_A falls in the 100 bin; therefore, the output of the ADC would be 100.
* Note that, for an N-bit ADC, there would be 2^N bins.

ADC: introduction





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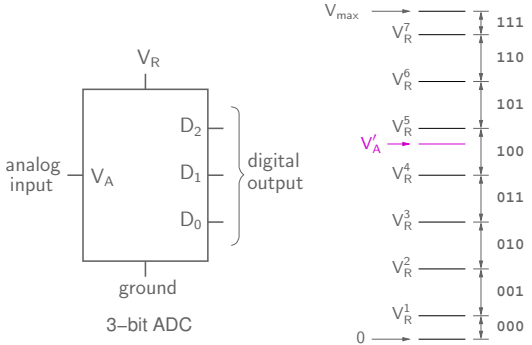
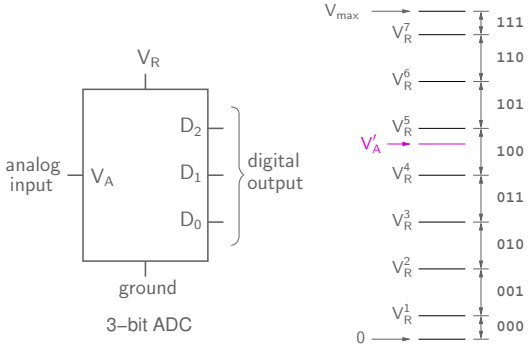
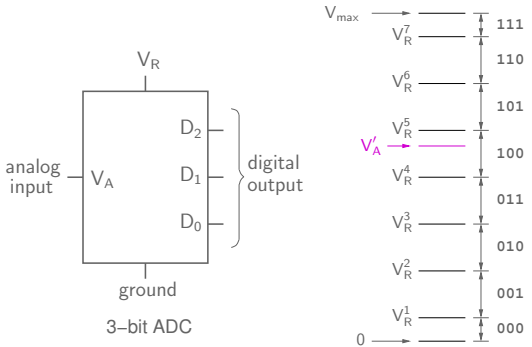


* The basic idea behind an ADC is simple:

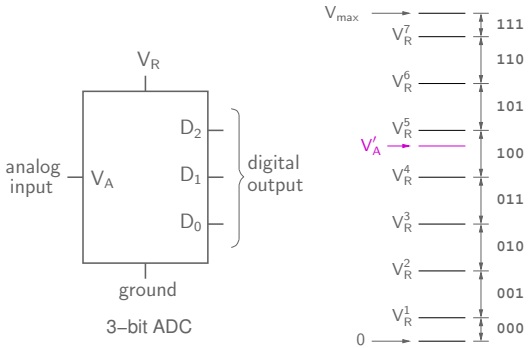
ADC: introduction



* The basic idea behind an ADC is simple:
  - Generate reference voltages V_R^1, V_R^2, etc.



* The basic idea behind an ADC is simple:
  - Generate reference voltages V_R^1, V_R^2, etc.
  - Compare the input V_A with each of V_R^i to figure out which bin it belongs to.



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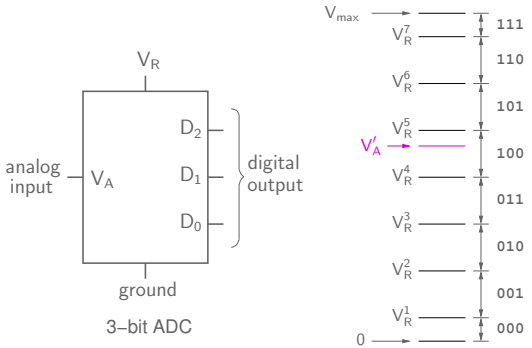

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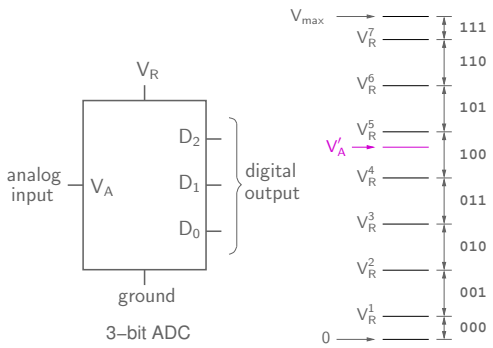
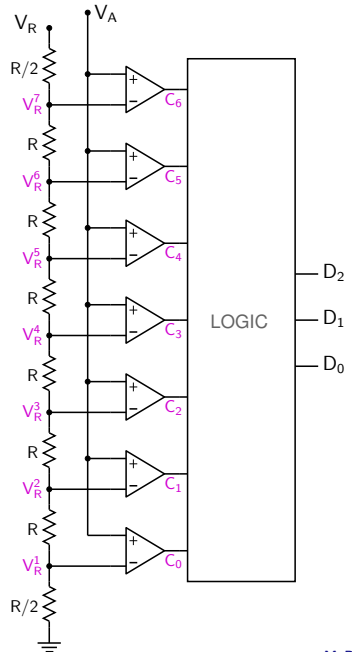
* A "parallel" ADC does exactly that → next slide.

3-bit parallel (flash) ADC





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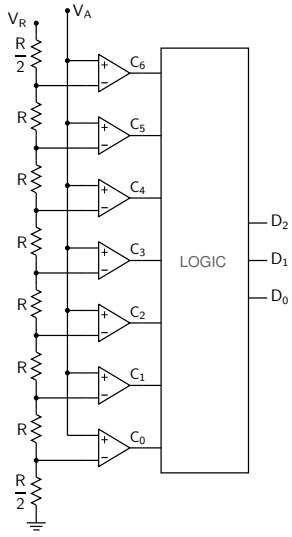

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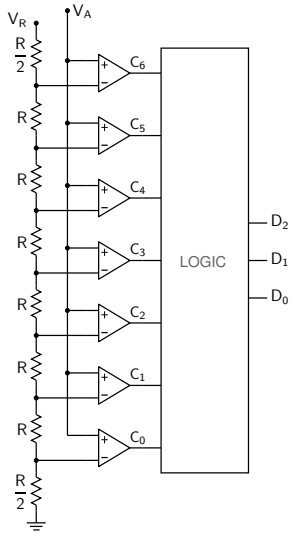

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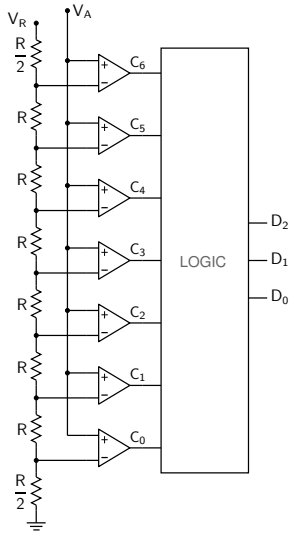

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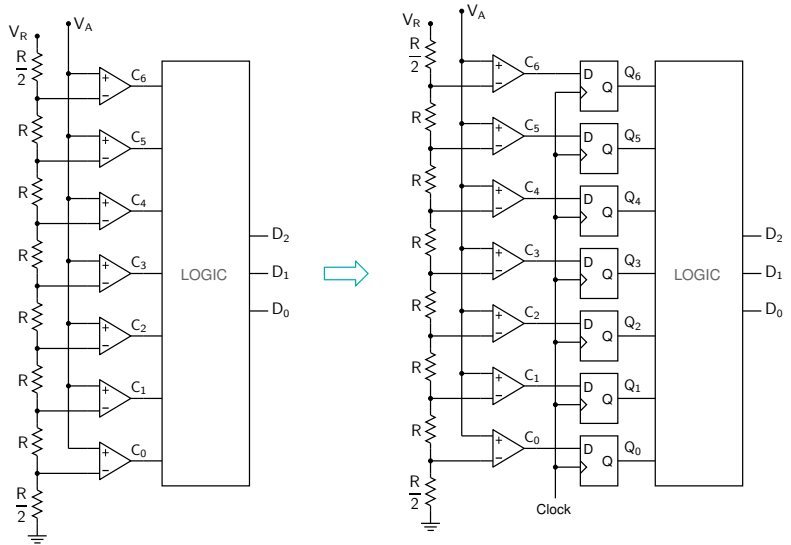

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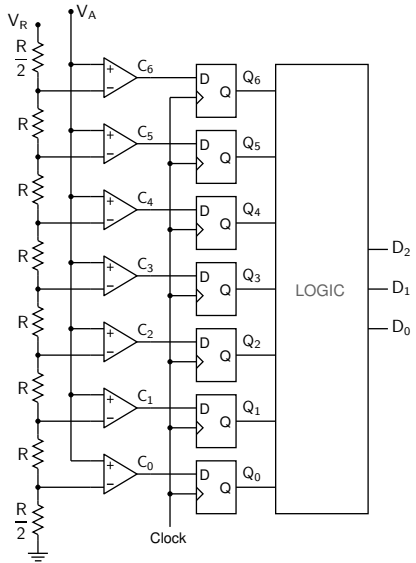

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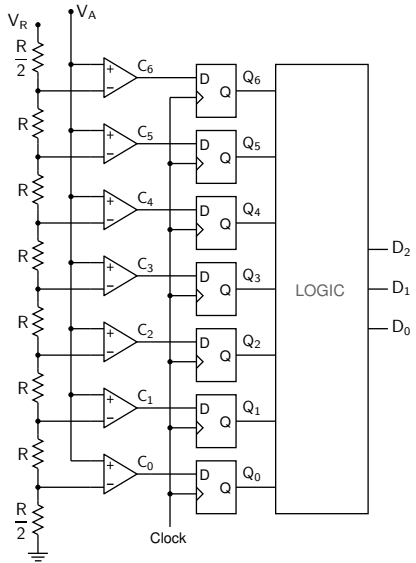

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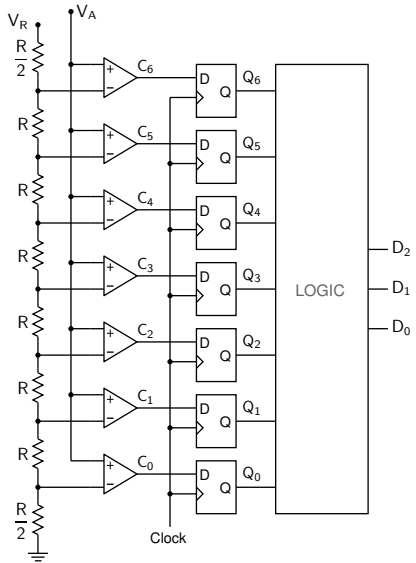

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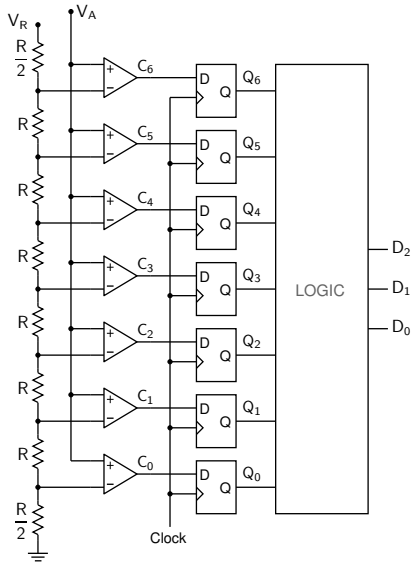

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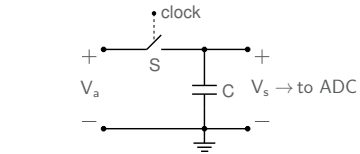
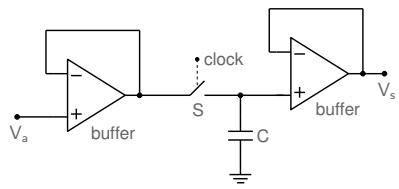
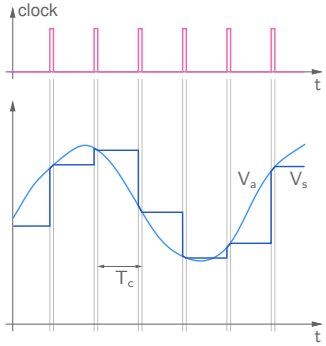
ADC: sampling of input signal







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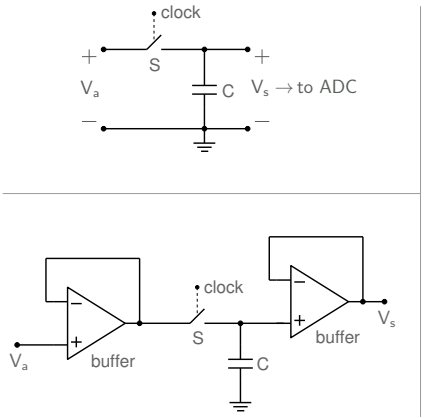

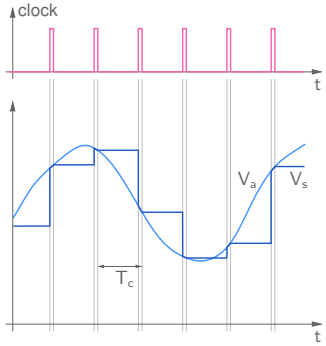

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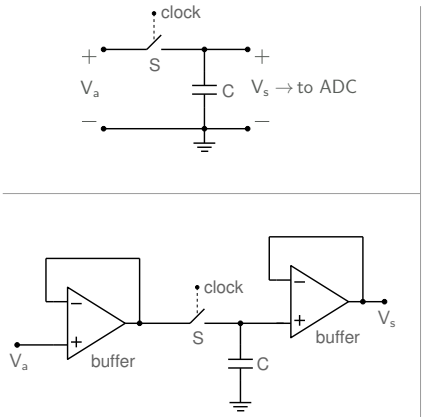

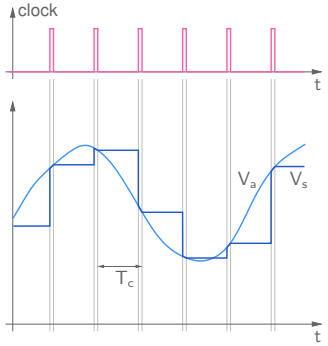

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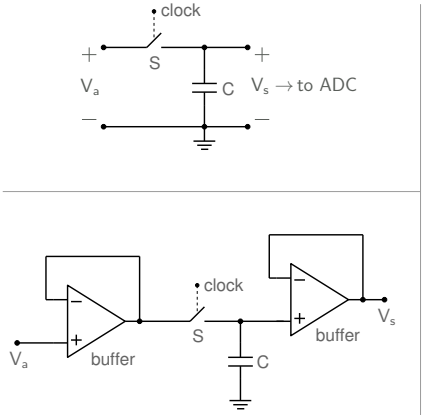

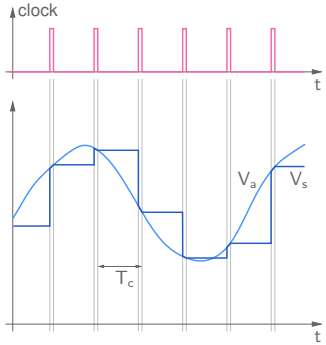

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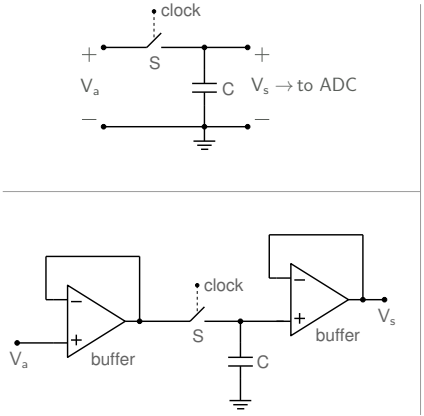

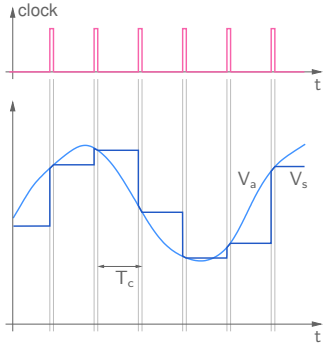

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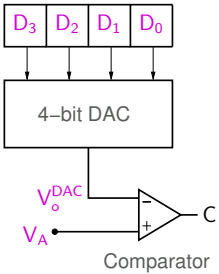
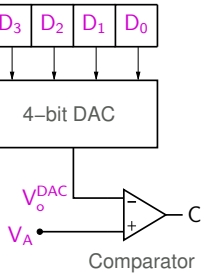

D3
D2
D1
D0
4–bit DAC
V_o^DAC
V_A
C
Comparator



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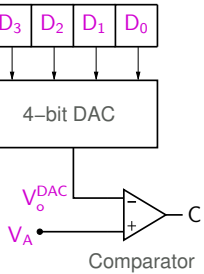

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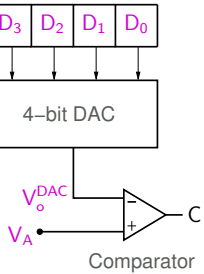

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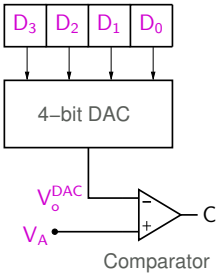

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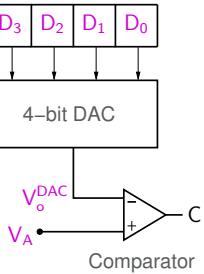

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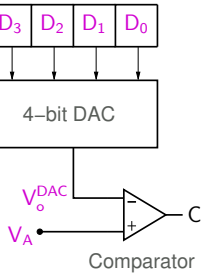

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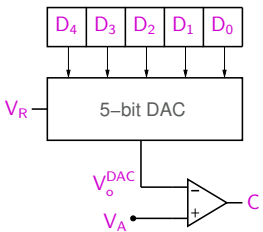
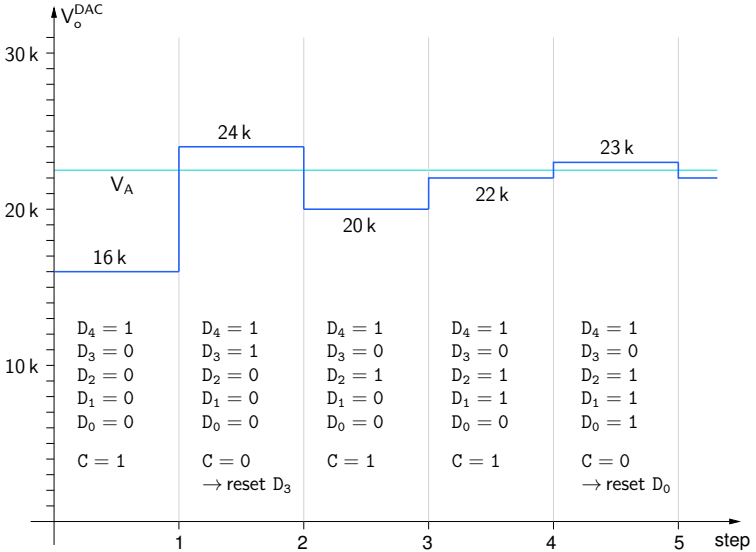
* At the end of four steps, the digital output is given by $D_3D_2D_1D_0$.
  Example $\rightarrow$ next slide.

Successive Approximation ADC



(Note: k $\propto V_R$)



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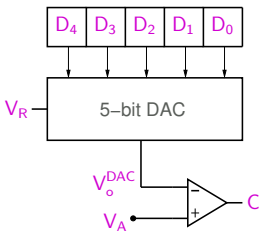

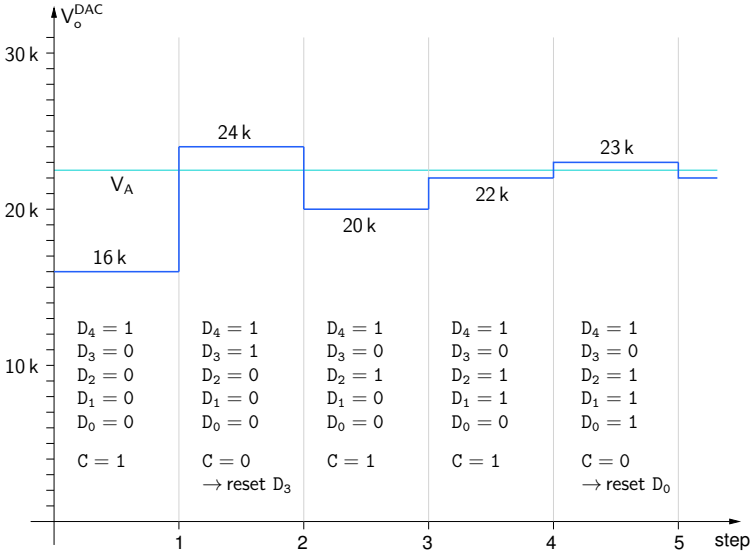

∗ At the end of the 5^{th} step, we know that the input voltage corresponds to 10110.

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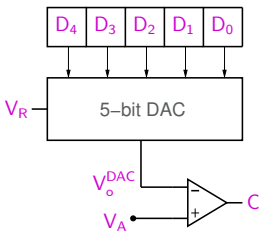

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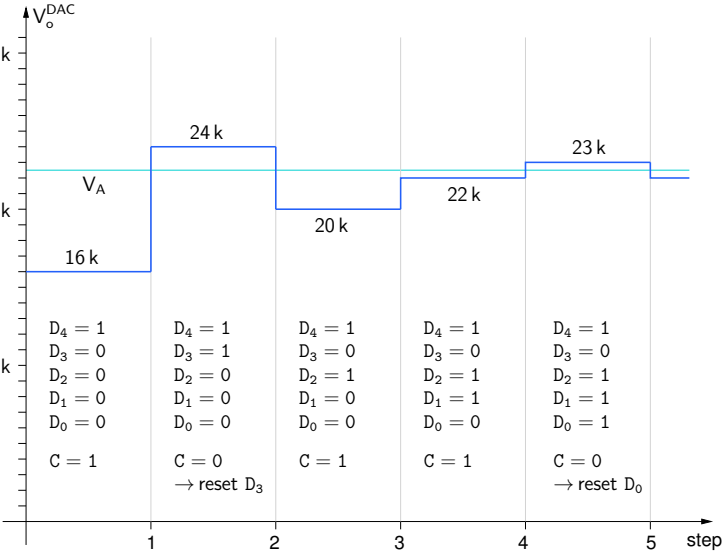
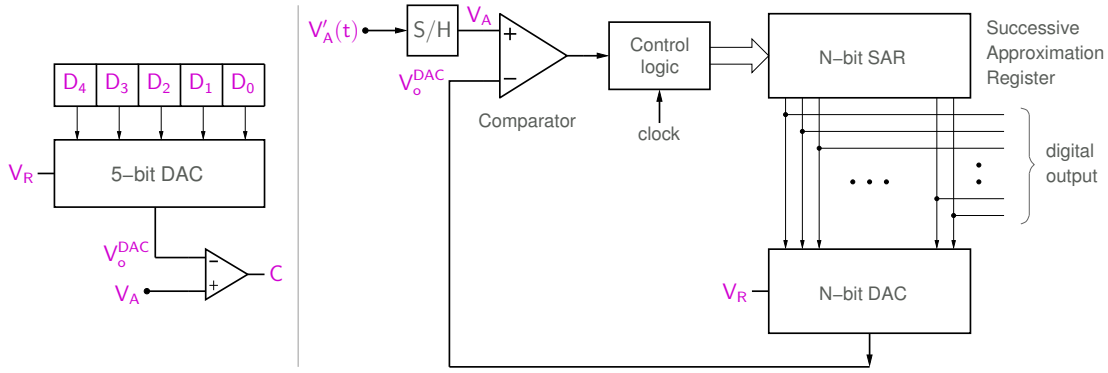
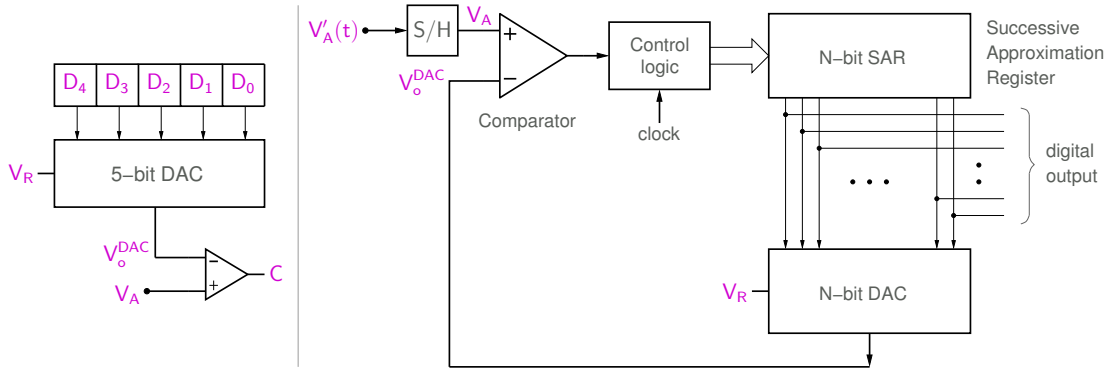
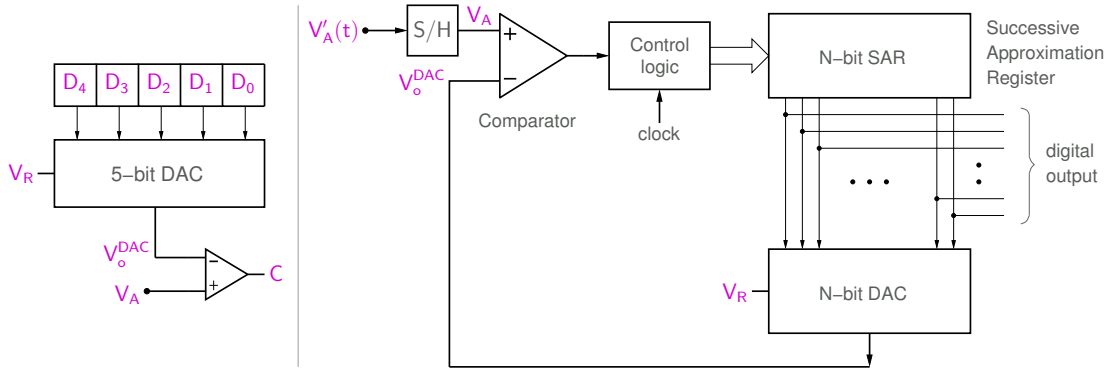


* At the end of the 5th step, we know that the input voltage corresponds to 10110.
* For the digital representation to be accurate up to $\pm\frac{1}{2}$ LSB, ΔV corresponding to $\frac{1}{2}$ LSB is added to V_A (see [Taub]).

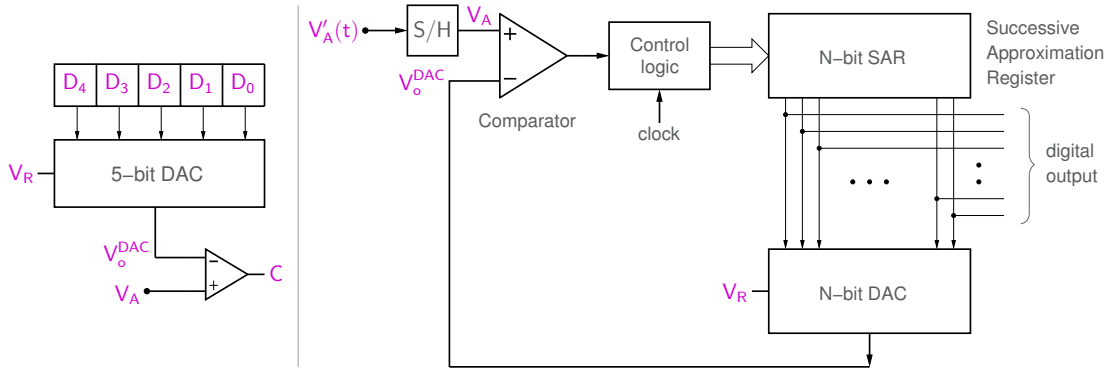

D4
D3
D2
D1
D0
VR
5–bit DAC
VoDAC
VA
C
V′A(t)
S/H
VA
VoDAC
Comparator
Control logic
clock
N–bit SAR
Successive Approximation Register
digital output
VR
N–bit DAC



* Each step (setting SAR bits, comparison of V_A and V_o^{DAC}) is performed in one clock cycle $\rightarrow$ conversion time is N cycles, irrespective of the input voltage value V_A.

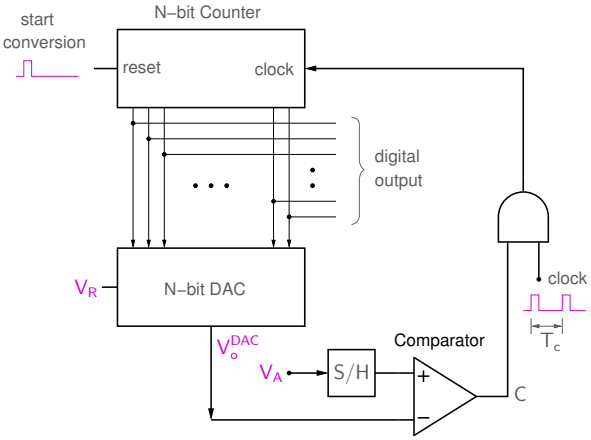


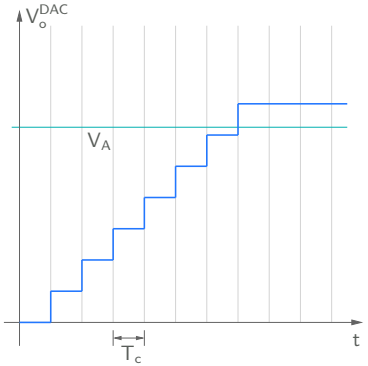
* Each step (setting SAR bits, comparison of V_A and V_o^{DAC}) is performed in one clock cycle $\rightarrow$ conversion time is N cycles, irrespective of the input voltage value V_A.
* S. A. ADCs with built-in or external S/H (sample-and-hold) are available for 8- to 16-bit resolution and conversion times of a few μsec to tens of μsec.



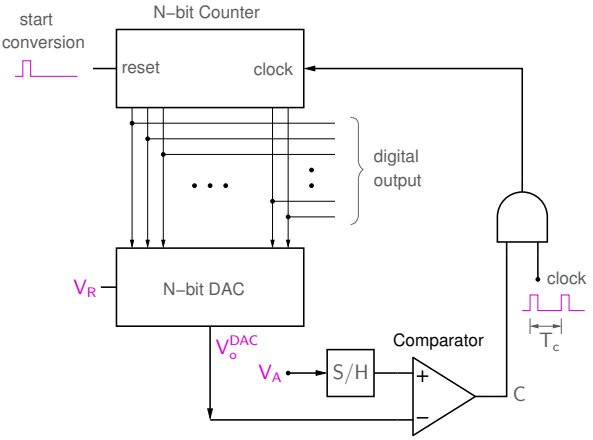
* Each step (setting SAR bits, comparison of V_A and V_o^{DAC}) is performed in one clock cycle $\rightarrow$ conversion time is N cycles, irrespective of the input voltage value V_A.
* S. A. ADCs with built-in or external S/H (sample-and-hold) are available for 8- to 16-bit resolution and conversion times of a few μsec to tens of μsec.
* Useful for medium-speed applications such as speech transmission with PCM.

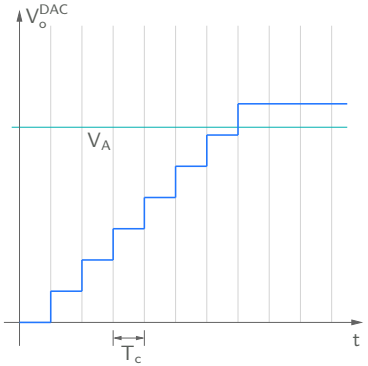
Counting ADC (digital-ramp ADC)





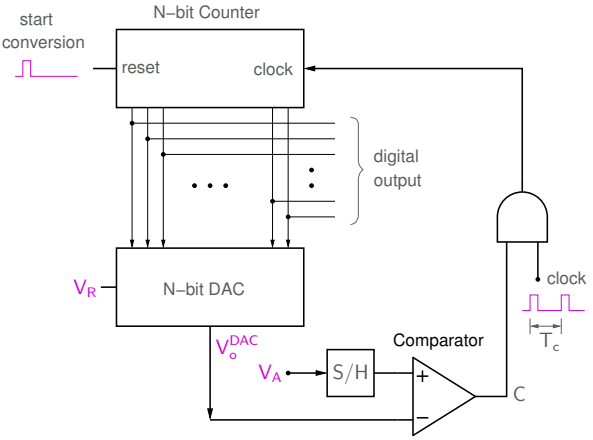
Counting ADC (digital-ramp ADC)

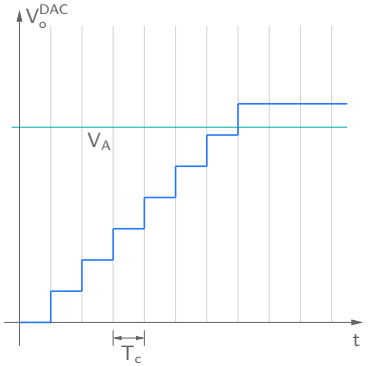




* The "start conversion" signal clears the counter; counting begins, and V_o^{DAC} increases with each clock cycle.

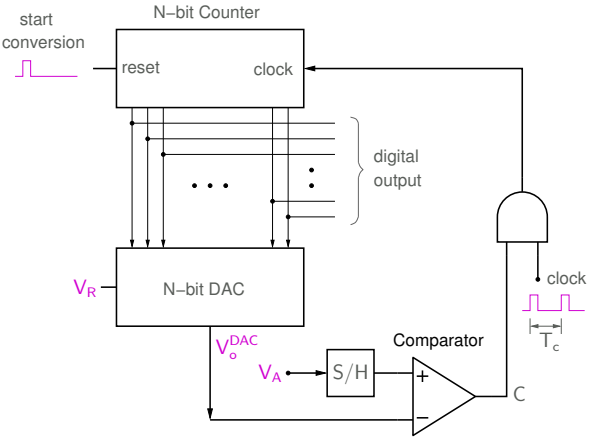
Counting ADC (digital-ramp ADC)

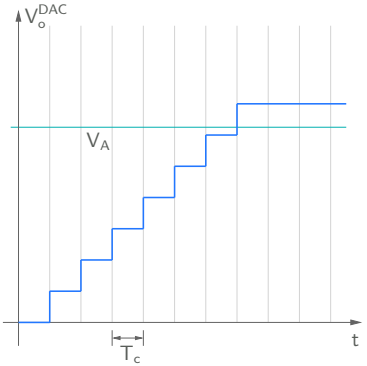




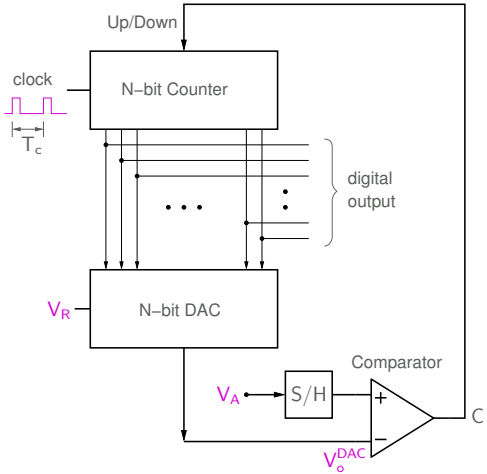
* The "start conversion" signal clears the counter; counting begins, and V_o^{DAC} increases with each clock cycle.
* When V_o^{DAC} exceeds V_A, C becomes 0, and counting stops.

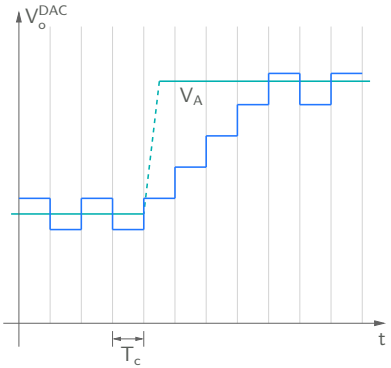
Counting ADC (digital-ramp ADC)

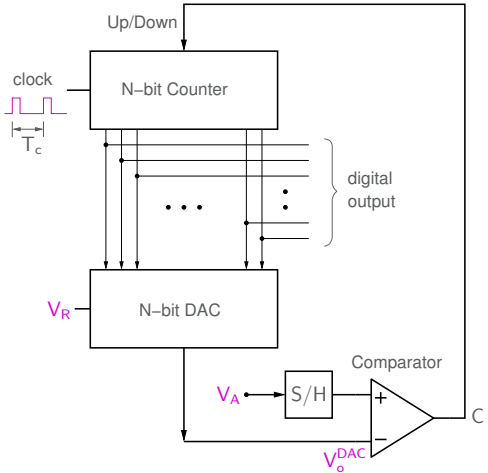


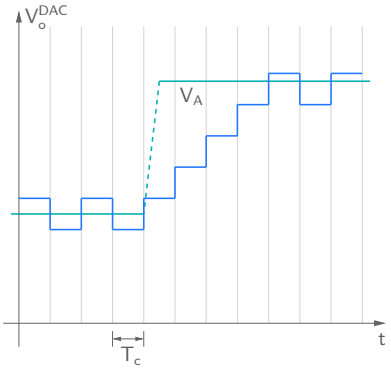


* The "start conversion" signal clears the counter; counting begins, and V_o^{DAC} increases with each clock cycle.
* When V_o^{DAC} exceeds V_A, C becomes 0, and counting stops.
* Simple scheme, but (a) conversion time depends on V_A, (b) slow (takes $(2^N - 1)$ clock cycles in the worst case) $\rightarrow$ tracking ADC

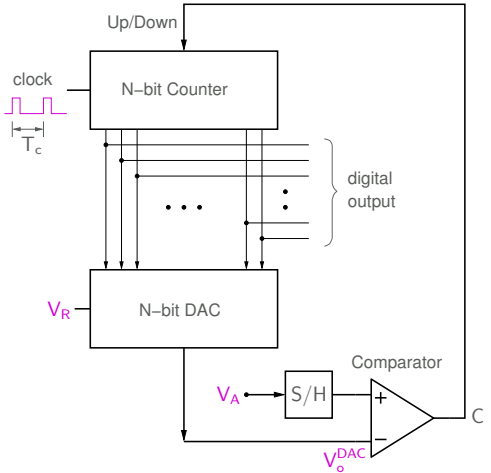

Up/Down
clock
N–bit Counter
T_c
digital
output
V_R
N–bit DAC
Comparator
V_A
S/H
+
−
C
V_o^{DAC}

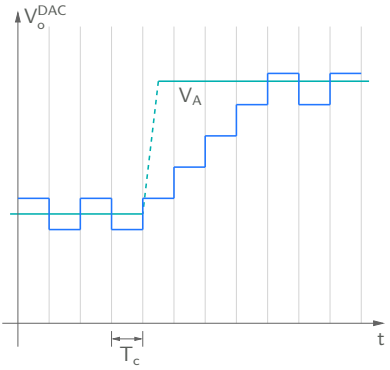

V_o^{DAC}
V_A
T_c
t



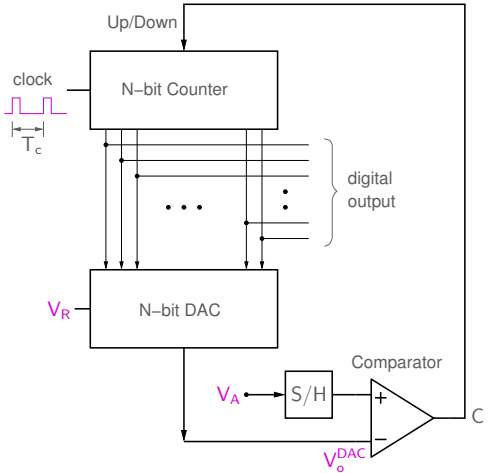


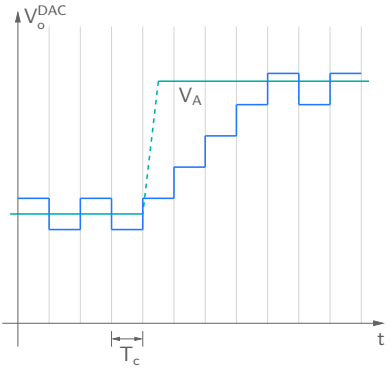
* The counter counts up if $V_o^{DAC} < V_A$; else, it counts down.



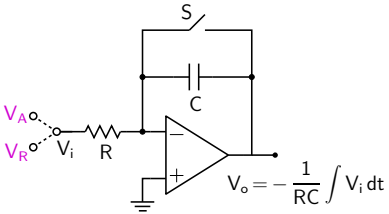


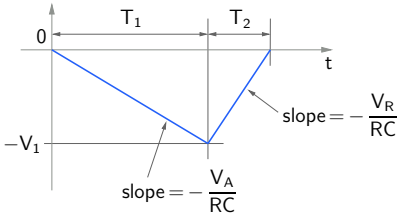
* The counter counts up if $V_o^{DAC} < V_A$; else, it counts down.
* If V_A changes, the counter does not need to start from $000\cdots0$, so the conversion time is less than that required by a counting ADC.

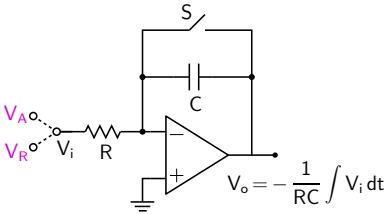


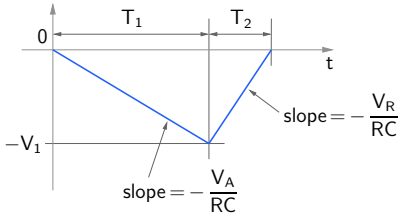


* The counter counts up if $V_o^{DAC} < V_A$; else, it counts down.
* If V_A changes, the counter does not need to start from $000\cdots0$, so the conversion time is less than that required by a counting ADC.
* used in low-cost, low-speed applications, e.g., measuring output from a temperature sensor or a strain gauge

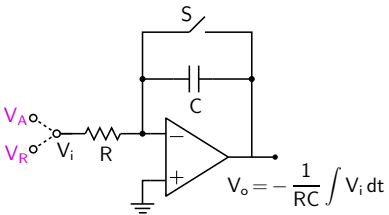

S
C
V_A
V_R
V_i
R
$V_o = -\frac{1}{RC}\int V_i\,dt$

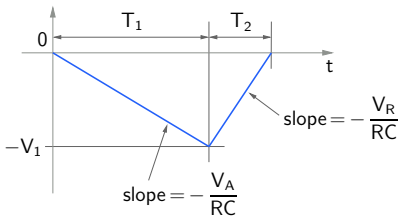

T_1
T_2
0
t
$-V_1$
slope $= -\frac{V_R}{RC}$
slope $= -\frac{V_A}{RC}$



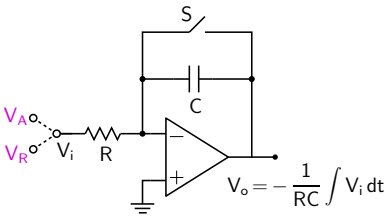


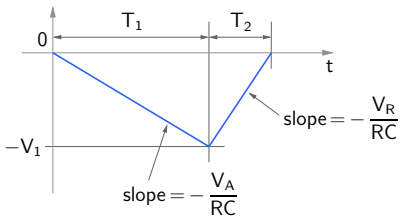
* $t = 0$: reset integrator output V_o to 0 V by closing S momentarily.



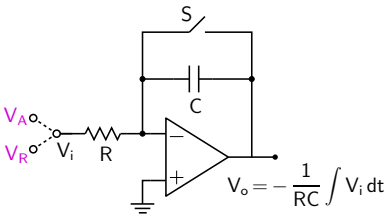


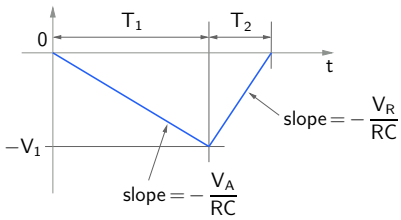
* $t = 0$: reset integrator output V_o to 0 V by closing S momentarily.
* Integrate V_A (voltage to be converted to digital format, assumed to be positive) for a fixed interval T_1.





* $t = 0$: reset integrator output V_o to 0 V by closing S momentarily.
* Integrate V_A (voltage to be converted to digital format, assumed to be positive) for a fixed interval T_1.
* At $t = T_1$, integrator output reaches $-V_1 = -V_A \frac{T_1}{RC}$.





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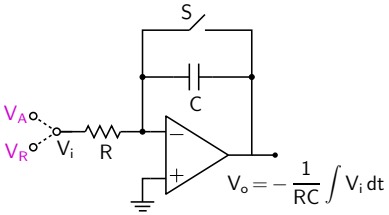
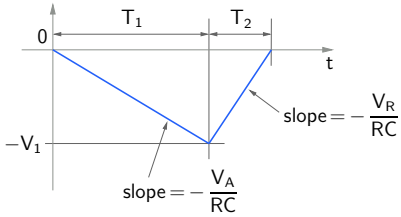
* Now apply a reference voltage V_R (assumed to be negative, with $|V_R| > V_A$), and integrate until V_o reaches 0 V.





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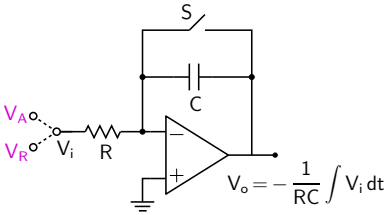
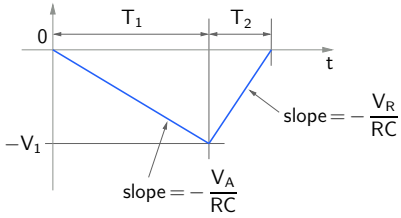
- At $t = T_1$, integrator output reaches $-V_1 = -V_A \frac{T_1}{RC}$.
- Now apply a reference voltage V_R (assumed to be negative, with $|V_R| > V_A$), and integrate until V_o reaches 0 V.
- Since $V_1 = V_A \frac{T_1}{RC} = |V_R| \frac{T_2}{RC}$, we have $T_2 = T_1 \frac{V_A}{|V_R|} \rightarrow T_2$ gives a measure of V_A.





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- Integrate V_A (voltage to be converted to digital format, assumed to be positive) for a fixed interval T_1.
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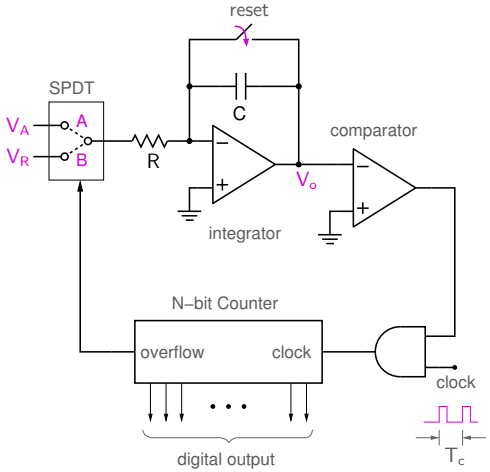
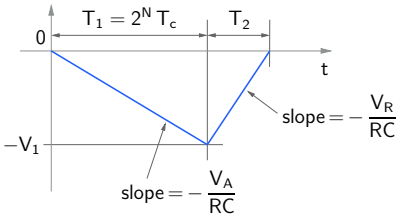
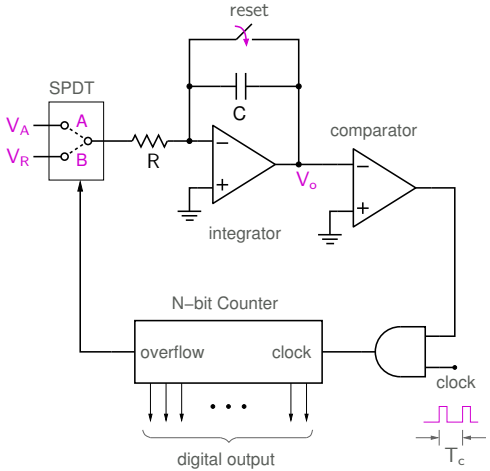
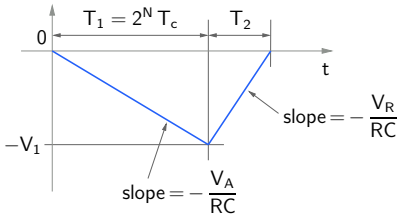
- Since $V_1 = V_A \frac{T_1}{RC} = |V_R| \frac{T_2}{RC}$, we have $T_2 = T_1 \frac{V_A}{|V_R|} \rightarrow T_2$ gives a measure of V_A.
- In the dual-slope ADC, a counter output – which is proportional to T_2 – provides the desired digital output.


reset
SPDT
V_A
V_R
A
B
R
C
comparator
V_o
integrator
N–bit Counter
overflow
clock
clock
digital output
T_c

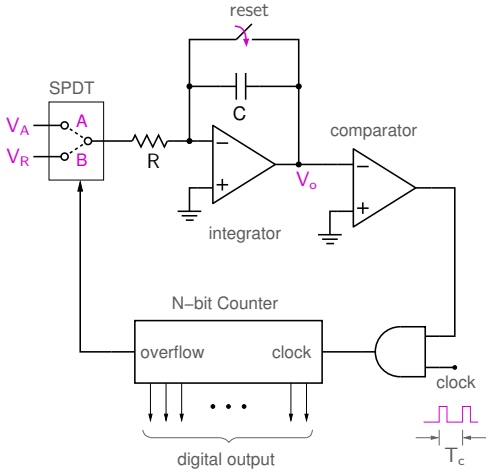

$T_1 = 2^N T_c$
T_2
0
t
$-V_1$
slope $= -\frac{V_R}{RC}$
slope $= -\frac{V_A}{RC}$

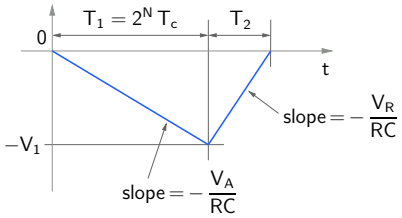




∗ Start: counter reset to 000 · · · 0, SPDT in position A.

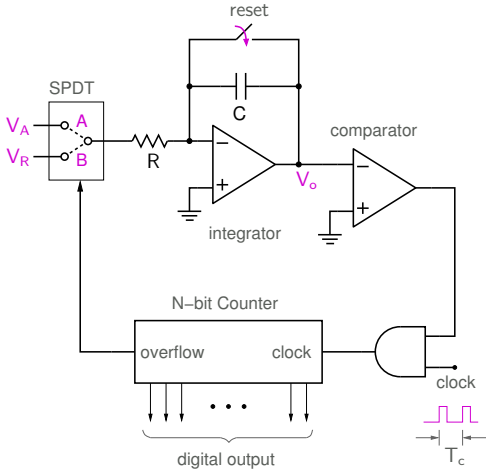
Dual-slope ADC

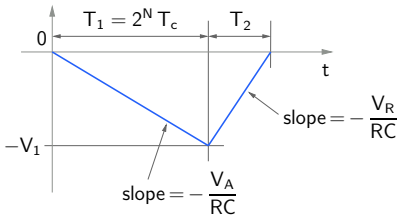




* Start: counter reset to $000\cdots0$, SPDT in position A.
* Counter counts up to 2^N at which point the overflow flag becomes 1, and SPDT switches to position B $\rightarrow$ $T_1 = 2^N\, T_c$ where T_c is the clock period.

Dual-slope ADC





* Start: counter reset to $000\cdots0$, SPDT in position A.
* Counter counts up to 2^N at which point the overflow flag becomes 1, and SPDT switches to position B $\rightarrow$ $T_1 = 2^N\, T_c$ where T_c is the clock period.
* The counter starts counting again from $000\cdots0$, and stops counting when V_o crosses 0 V. The counter output gives T_2 in binary format.

References

* K. Gopalan, *Introduction to Digital Microelectronic Circuits*, Tata McGraw-Hill, New Delhi, 1998.
* H. Taub and D. Schilling, *Digital Integrated Electronics*, McGraw-Hill, 1977.